LOW NOISE, HIGH SLEW RATE, UNITY GAIN STABLE VOLTAGE FEEDBACK AMPLIFIER

Check for Samples: THS4271-EP

FEATURES

- **Unity Gain Stability**
- **Low Voltage Noise**
  - **3 nV/√Hz**
- **High Slew Rate: 1000 V/μs**
- **Low Distortion**
  - **–92 dBc THD at 30 MHz**
- **Wide Bandwidth: 1.4 GHz**
- **Supply Voltages**
  - **+5 V, ±5 V**
- **Evaluation Module Available**

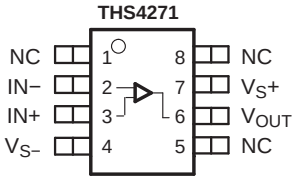
APPLICATIONS

- **High Linearity ADC Preamplifier**
- **Wireless Communication Receivers**
- **Differential to Single-Ended Conversion**
- **DAC Output Buffer**
- **Active Filtering**

SUPPORTS DEFENSE, AEROSPACE, AND MEDICAL APPLICATIONS

- **Controlled Baseline**
- **One Assembly/Test Site**
- **One Fabrication Site**
- **Available in Military (–55°C/125°C) Temperature Range**(1)
- **Extended Product Life Cycle**
- **Extended Product-Change Notification**
- **Product Traceability**

(1) Additional temperature ranges are available - contact factory



DESCRIPTION

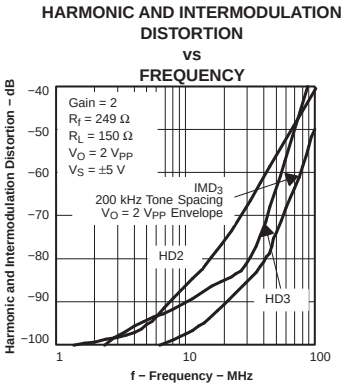
The THS4271 is a low-noise, high slew rate, unity gain stable voltage-feedback amplifier designed to run from supply voltages as low as 5 V. The combination of low-noise, high slew rate, wide bandwidth, low distortion, and unity gain stability make the THS4271 a high performance device across multiple ac specifications.

Designers using the THS4271 are rewarded with higher dynamic range over a wider frequency band without the stability concerns of decompensated amplifiers. The devices are available in SOIC, MSOP with PowerPAD™, and leadless MSOP with PowerPAD™ packages.

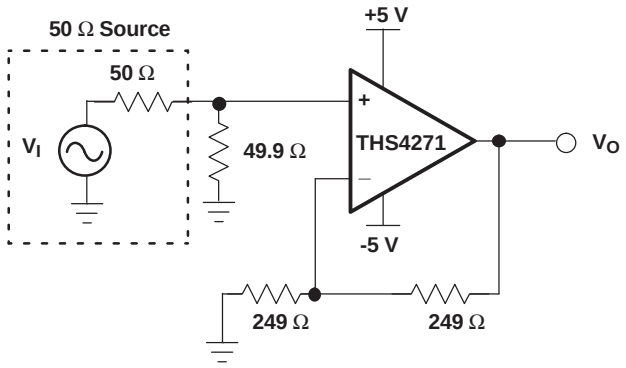
The THS4271 may have low-level oscillation when the die temperature (also known as the *junction temperature*) exceeds +60°C and is not recommended for new designs. For more information, see Maximum Die Temperature to Prevent Oscillation.

RELATED DEVICES

DEVICE	DESCRIPTION
THS4211	1-GHz voltage-feedback amplifier
THS4503	Wideband, fully-differential amplifier
THS3202	Dual, wideband current feedback amplifier



Low-Noise, Low-Distortion, Wideband Application Circuit



NOTE: Power supply decoupling capacitors not shown

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

PACKAGING/ORDERING INFORMATION(1)

ORDERABLE PACKAGE AND NUMBER	
PLASTIC MSOP(2) PowerPAD	
PACKAGE	PACKAGE MARKING
THS4271MDGNTEP	BLT
THS4271MDGNREP	

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

(2) All packages are available taped and reeled. The R suffix standard quantity is 2500 (e.g., THS4271MDGNREP).

ABSOLUTE MAXIMUM RATINGS

Over operating free-air temperature range unless otherwise noted(1)

			UNIT
V_S	Supply voltage		16.5 V
V_I	Input voltage		$\pm V_S$
I_O	Output current		100 mA
	Continuous power dissipation		See Dissipation Ratings Table
T_J	Maximum junction temperature		+150°C
T_J (2)	Maximum junction temperature, continuous operation long term reliability		+125°C
T_J (3)	Maximum junction temperature to prevent oscillation		+60°C
T_{stg}	Storage temperature range		–65°C to +150°C
	Lead temperature (1,6 mm (1/16 inch) from case for 10 seconds)		+300°C
	ESD ratings	HBM	3000 V
		CDM	1000 V
		MM	100 V

(1) The absolute maximum temperature under any condition is limited by the constraints of the silicon process. Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those specified is not implied.

(2) Long-term high-temperature storage and/or extended use at maximum recommended operating conditions may result in a reduction of overall device life. See Figure 1 for additional information on thermal derating.

(3) See *Maximum Die Temperature to Prevent Oscillation* section in the *Application Information* of this data sheet.

PACKAGE DISSIPATION RATINGS

PACKAGE	θ_{JC} (°C/W)	θ_{JA} (1) (°C/W)
DGN (8 pin) (2)	4.7	58.4

(1) This data was taken using the JEDEC standard High-K test PCB.

(2) The THS4271 may incorporate a PowerPAD™ on the underside of the chip. This feature acts as a heat sink and must be connected to a thermally dissipative plane for proper power dissipation. Failure to do so may result in exceeding the maximum junction temperature which could permanently damage the device. See TI technical briefs SLMA002 and SLMA004 for more information about utilizing the PowerPAD thermally enhanced package.

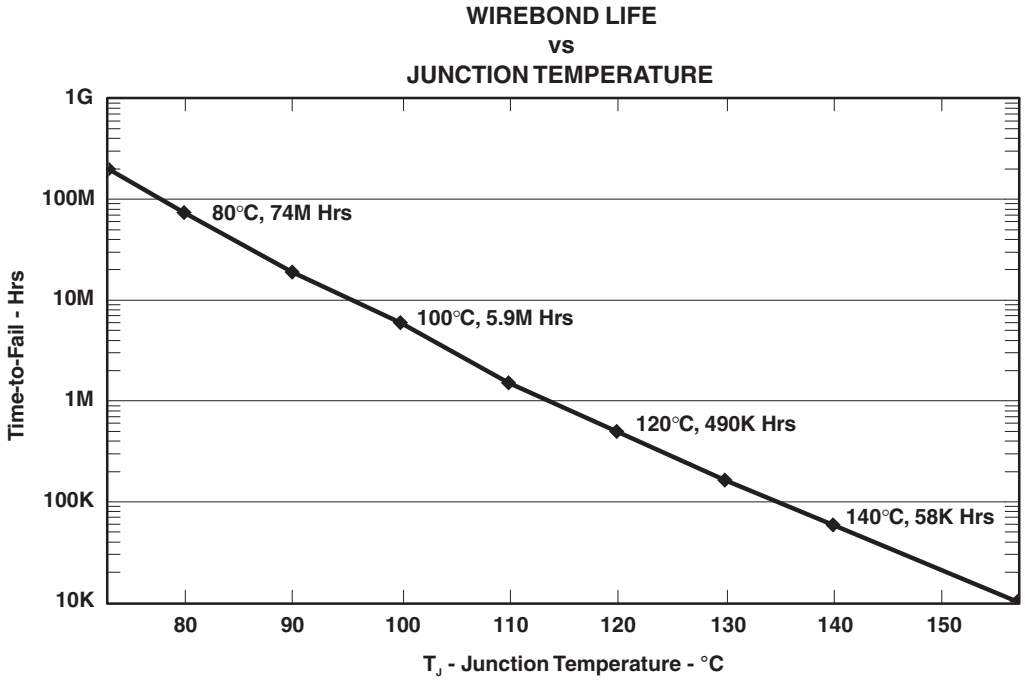
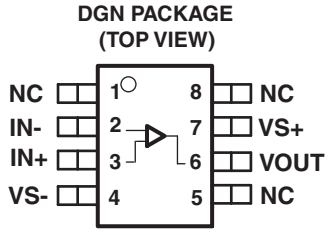


Figure 1. EME−G600 Estimated Wirebond Life

RECOMMENDED OPERATING CONDITIONS

		MIN	MAX	UNIT
Supply voltage (V_{S+} and V_{S-})	Dual supply	±2.5	±5	V
	Single supply	5	10	
Input common-mode voltage range		V_{S-} + 1.4	V_{S+} – 1.4	V

PIN ASSIGNMENTS



NC - No internal connection

ELECTRICAL CHARACTERISTICS: V_S = ±5 V

At R_F = 249 Ω, R_L = 499 Ω, G = +2, unless otherwise noted.

PARAMETER	TEST CONDITIONS	TYP	OVER TEMPERATURE(1)		UNITS	MIN/ TYP/ MAX
		+25°C	+25°C	–55°C to +125°C		
AC PERFORMANCE						
Small-signal bandwidth	G = 1, V_O = 100 mV_{PP}, R_L = 150 Ω	1.4			GHz	Typ
	G = –1, V_O = 100 mV_{PP}	400			MHz	Typ
	G = 2, V_O = 100 mV_{PP}	390			MHz	Typ
	G = 5, V_O = 100 mV_{PP}	85			MHz	Typ
	G = 10, V_O = 100 mV_{PP}	40			MHz	Typ
0.1-dB flat bandwidth	G = 1, V_O = 100 mV_{PP}, R_L = 150 Ω	200			MHz	Typ
Gain bandwidth product	G > 10, f = 1 MHz	400			MHz	Typ
Full-power bandwidth	G = –1, V_O = 2 V_p	80			MHz	Typ
Slew rate	G = 1, V_O = 2 V Step	950			V/µs	Typ
	G = –1, V_O = 2 V Step	1000			V/µs	Typ
Settling time to 0.1%	G = –1, V_O = 4 V Step	25			ns	Typ
Settling time to 0.01%	G = –1, V_O = 4 V Step	38			ns	Typ
Harmonic distortion	G = 1, V_O = 1 V_{PP}, f = 30 MHz					
Second harmonic distortion	R_L = 150 Ω	-92			dBc	Typ
	R_L = 499 Ω	-80			dBc	Typ
Third harmonic distortion	R_L = 150 Ω	-95			dBc	Typ
	R_L = 499 Ω	-95			dBc	Typ
Harmonic distortion	G = 2, V_O = 2 V_{PP}, f = 30 MHz					
Second harmonic distortion	R_L = 150 Ω	-65			dBc	Typ
	R_L = 499 Ω	-70			dBc	Typ
Third harmonic distortion	R_L = 150 Ω	-80			dBc	Typ
	R_L = 499 Ω	-90			dBc	Typ
Third-order intermodulation (IMD_3)	G = 2, V_O = 2 V_{PP}, R_L = 150 Ω, f = 70 MHz	-60			dBc	Typ
Third-order output intercept (OIP_3)	G = 2, V_O = 2 V_{PP}, R_L = 150Ω, f = 70 MHz	35			dBm	Typ
Differential gain (NTSC, PAL)	G = 2, R_L = 150 Ω	0.007%				Typ
Differential phase (NTSC, PAL)	G = 2, R_L = 150 Ω	0.004			°	Typ
Input voltage noise	f = 1 MHz	3			nV/√Hz	Typ
Input current noise	f = 1 MHz	3			pA√Hz	Typ
DC PERFORMANCE						
Open-loop voltage gain (A_{OL})	V_O = ± 50 mV, R_L = 499 Ω	75	65	56	dB	Min
Input offset voltage	V_{CM} = 0 V	5	14	±16	mV	Max
Average offset voltage drift	V_{CM} = 0 V			±10	µV/°C	Typ
Input bias current	V_{CM} = 0 V	6	15	18	µA	Max
Average bias current drift	V_{CM} = 0 V			±10	nA/°C	Typ
Input offset current	V_{CM} = 0 V	1	6	8	µA	Max
Average offset current drift	V_{CM} = 0 V			±10	nA/°C	Typ
INPUT CHARACTERISTICS						
Common-mode input range		±4	±3.6	±3.5	V	Min
Common-mode rejection ratio	V_{CM} = ± 2 V	72	67	62	dB	Min
Input resistance	Common-mode	5			MΩ	Typ

(1) See application section "Maximum Die Temperature to Prevent Oscillation".

ELECTRICAL CHARACTERISTICS: V_S = ±5 V (continued)

At R_F = 249 Ω, R_L = 499 Ω, G = +2, unless otherwise noted.

PARAMETER	TEST CONDITIONS	TYP	OVER TEMPERATURE(1)		UNITS	MIN/ TYP/ MAX
		+25°C	+25°C	–55°C to +125°C		
Input capacitance	Common-mode / differential	0.4/0.8			pF	Typ
OUTPUT CHARACTERISTICS						
Output voltage swing	G = +2	±4	±3.75	±3.6	V	Min
Output current (sourcing)	R_L = 10 Ω	160	120	104	mA	Min
Output current (sinking)	R_L = 10 Ω	80	60	44	mA	Min
Output impedance	f = 1 MHz	0.1			Ω	Typ
POWER SUPPLY						
Specified operating voltage		±5	±5	±5	V	Max
Maximum quiescent current		22	24	34	mA	Max
Minimum quiescent current		22	20	13	mA	Min
Power-supply rejection (+PSRR)	V_{S+} = 5.5 V to 4.5 V, $V_{S–}$ = 5 V	85	75	58	dB	Min
Power-supply rejection (-PSRR)	V_{S+} = 5 V, $V_{S–}$ = -5.5 V to -4.5 V	75	65	57	dB	Min

ELECTRICAL CHARACTERISTICS: V_S = 5 V

At R_F = 249 Ω, R_L = 499 Ω, G = +2, unless otherwise noted.

PARAMETER	TEST CONDITIONS	TYP	OVER TEMPERATURE(1)			MIN/ TYP/ MAX
		+25°C	+25°C	–55°C to +125°C	UNITS	
AC PERFORMANCE						
Small-signal bandwidth	G = 1, V_O = 100 mV_{PP}, R_L = 150 Ω	1.2			GHz	Typ
	G = –1, V_O = 100 mV_{PP}	380			MHz	Typ
	G = 2, V_O = 100 mV_{PP}	360			MHz	Typ
	G = 5, V_O = 100 mV_{PP}	80			MHz	Typ
	G = 10, V_O = 100 mV_{PP}	35			MHz	Typ
0.1-dB flat bandwidth	G = 1, V_O = 100 mV_{PP}, R_L = 150 Ω	120			MHz	Typ
Gain bandwidth product	G > 10, f = 1 MHz	350			MHz	Typ
Full-power bandwidth	G = –1, V_O = 2 V_p	60			MHz	Typ
Slew rate	G = 1, V_O = 2 V Step	700			V/µs	Typ
	G = –1, V_O = 2 V Step	750			V/µs	Typ
Settling time to 0.1%	G = –1, V_O = 2 V Step	18			ns	Typ
Settling time to 0.01%	G = –1, V_O = 2 V Step	66			ns	Typ
Harmonic distortion	G = 1, V_O = 1 V_{PP}, f = 30 MHz					
Second harmonic distortion	R_L = 150 Ω	75			dBc	Typ
	R_L = 499 Ω	72			dBc	Typ
Third harmonic distortion	R_L = 150 Ω	-70			dBc	Typ
	R_L = 499 Ω	70			dBc	Typ
Third-order intermodulation (IMD_3)	G = 2, V_O = 1 V_{PP}, R_L = 150Ω, f = 70 MHz	-65			dBc	Typ
Third-order output intercept (OIP_3)	G = 2, V_O = 1 V_{PP}, R_L = 150Ω, f = 70 MHz	32			dBm	Typ
Input voltage noise	f = 1 MHz	3			nV/√Hz	Typ
Input current noise	f = 10 MHz	3			pA/√Hz	Typ
DC PERFORMANCE						
Open-loop voltage gain (A_{OL})	V_O = ± 50 mV, R_L = 499 Ω	68	63	56	dB	Min
Input offset voltage	V_{CM} = V_S/2	5	±14	±16	mV	Max
Average offset voltage drift	V_{CM} = V_S/2			±10	µV/°C	Typ
Input bias current	V_{CM} = V_S/2	6	15	18	µA	Max
Average bias current drift	V_{CM} = V_S/2			±10	nA/°C	Typ
Input offset current	V_{CM} = V_S/2	1	6	8	µA	Max
Average offset current drift	V_{CM} = V_S/2			±10	nA/°C	Typ
INPUT CHARACTERISTICS						
Common-mode input range		1/4	1.3/3.7	1.5/3.5	V	Min
Common-mode rejection ratio	V_{CM} = ± 0.5 V, V_O = 2.5 V	72	67	62	dB	Min
Input resistance	Common-mode	5			MΩ	Typ
Input capacitance	Common-mode / differential	0.4/0.8			pF	Typ
OUTPUT CHARACTERISTICS						
Output voltage swing	G = +2	1.2/3.8	1.4/3.6	1.5/3.5	V	Min
Output current (sourcing)	R_L = 10 Ω	120	90	78	mA	Min
Output current (sinking)	R_L = 10 Ω	65	45	37	mA	Min
Output impedance	f = 1 MHz	0.1			Ω	Typ

(1) See application section "Maximum Die Temperature to Prevent Oscillation".

ELECTRICAL CHARACTERISTICS: V_S = 5 V (continued)

At R_F = 249 Ω, R_L = 499 Ω, G = +2, unless otherwise noted.

PARAMETER	TEST CONDITIONS	TYP	OVER TEMPERATURE(1)			MIN/ TYP/ MAX
		+25°C	+25°C	–55°C to +125°C	UNITS	
POWER SUPPLY						
Specified operating voltage		5	10	10	V	Max
Maximum quiescent current		20	23	34	mA	Max
Minimum quiescent current		20	18	13	mA	Min
Power-supply rejection (+PSRR)	V_{S+} = 5.5 V to 4.5 V, $V_{S–}$ = 0 V	85	70	57	dB	Min
Power-supply rejection (-PSRR)	V_{S+} = 5 V, $V_{S–}$ = –0.5 V to 0.5 V	75	65	56	dB	Min

TYPICAL CHARACTERISTICS

Table of Graphs (±5 V)

		FIGURE
Small-signal unity gain frequency response		1
Small-signal frequency response		2
0.1-dB gain flatness frequency response		3
Large-signal frequency response		4
Slew rate	vs Output voltage	5
Harmonic distortion	vs Frequency	6, 7, 8, 9
Harmonic distortion	vs Output voltage swing	10, 11, 12, 13
Third-order intermodulation distortion	vs Frequency	14, 16
Third-order intercept point	vs Frequency	15, 17
Voltage and current noise	vs Frequency	18
Differential gain	vs Number of loads	19
Differential phase	vs Number of loads	20
Settling time		21
Quiescent current	vs Supply voltage	22
Output voltage	vs Load resistance	23
Frequency response	vs Capacitive load	24
Open-loop gain and phase	vs Frequency	25
Open-loop gain	vs Supply voltage	26
Rejection ratios	vs Frequency	27
Rejection ratios	vs Case temperature	28
Common-mode rejection ratio	vs Input common-mode range	29
Input offset voltage	vs Case temperature	30
Input bias and offset current	vs Case temperature	31
Small-signal transient response		32
Large-signal transient response		33
Overdrive recovery		34
Closed-loop output impedance	vs Frequency	35
Power-down quiescent current	vs Supply voltage	36
Power-down output impedance	vs Frequency	37
Turn-on and turn-off delay times		38

Table of Graphs (5 V)

		FIGURE
Small-signal unity gain frequency response		39
Small-signal frequency response		40
0.1-dB gain flatness frequency response		41
Large-signal frequency response		42
Slew rate	vs Output voltage	43
Harmonic distortion	vs Frequency	44, 45, 46, 47
Harmonic distortion	vs Output voltage swing	48, 49, 50, 51
Third-order intermodulation distortion	vs Frequency	52, 54
Third-order intercept point	vs Frequency	53, 55
Voltage and current noise	vs Frequency	56
Settling time		57
Quiescent current	vs Supply voltage	58
Output voltage	vs Load resistance	59
Frequency response	vs Capacitive load	60
Open-loop gain and phase	vs Frequency	61
Open-loop gain	vs Case temperature	62
Rejection ratios	vs Frequency	63
Rejection ratios	vs Case temperature	64
Common-mode rejection ratio	vs Input common-mode range	65
Input offset voltage	vs Case temperature	66
Input bias and offset current	vs Case temperature	67
Small-signal transient response		68
Large-signal transient response		69
Overdrive recovery		70
Closed-loop output impedance	vs Frequency	71
Power-down quiescent current	vs Supply voltage	72
Power-down output impedance	vs Frequency	73
Turn-on and turn-off delay times		74

TYPICAL CHARACTERISTICS: ±5 V

SMALL-SIGNAL UNIT GAIN FREQUENCY RESPONSE

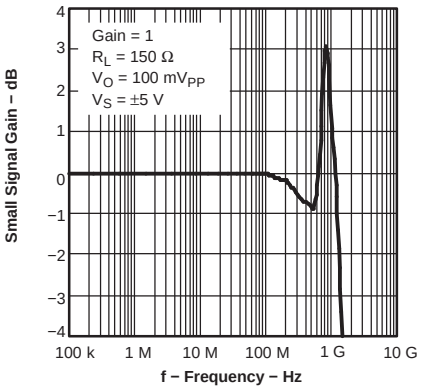


Figure 2.

SMALL-SIGNAL FREQUENCY RESPONSE

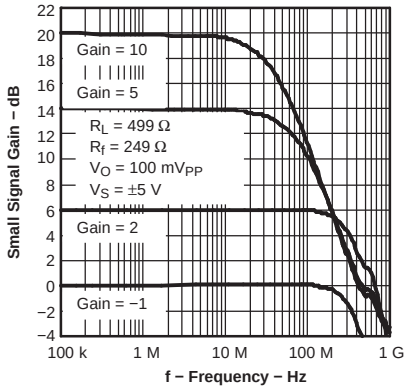


Figure 3.

0.1-dB GAIN FLATNESS FREQUENCY RESPONSE

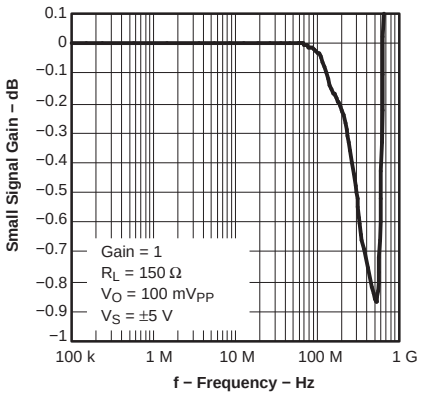


Figure 4.

LARGE-SIGNAL FREQUENCY RESPONSE

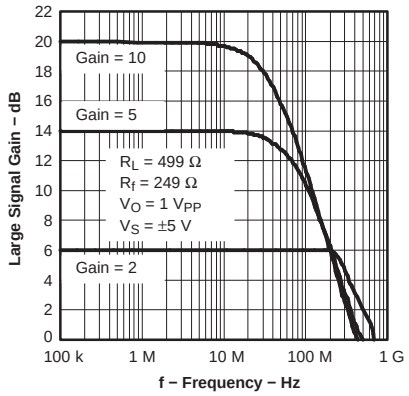


Figure 5.

SLEW RATE vs OUTPUT VOLTAGE

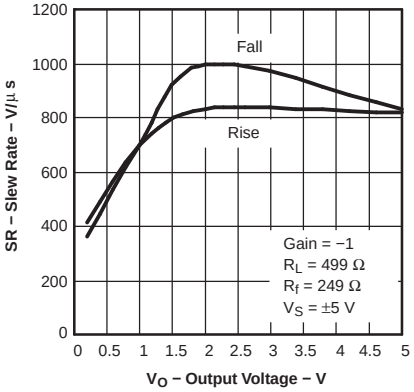


Figure 6.

HARMONIC DISTORTION vs FREQUENCY

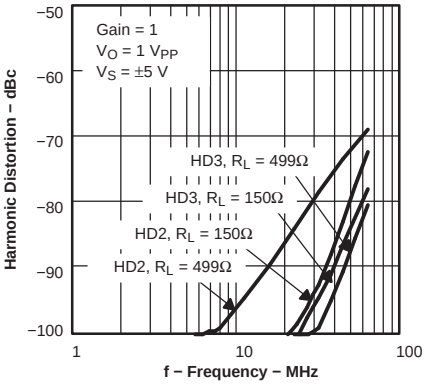


Figure 7.

HARMONIC DISTORTION vs FREQUENCY

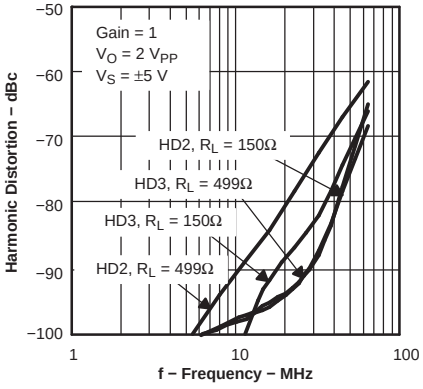


Figure 8.

HARMONIC DISTORTION vs FREQUENCY

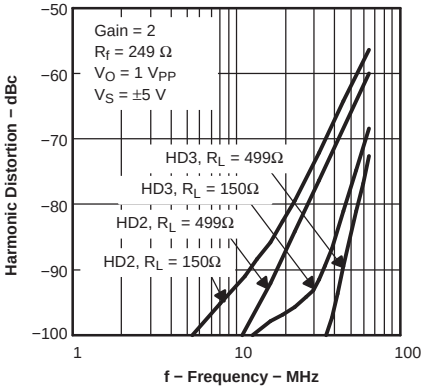


Figure 9.

HARMONIC DISTORTION vs FREQUENCY

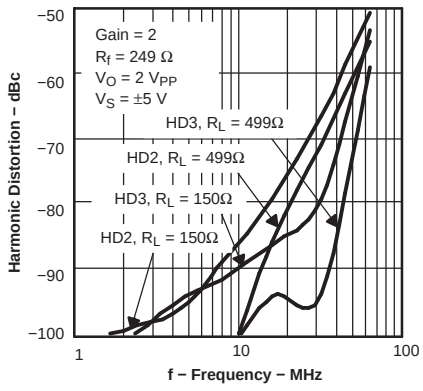


Figure 10.

TYPICAL CHARACTERISTICS: ±5 V (continued)

HARMONIC DISTORTION vs OUTPUT VOLTAGE SWING

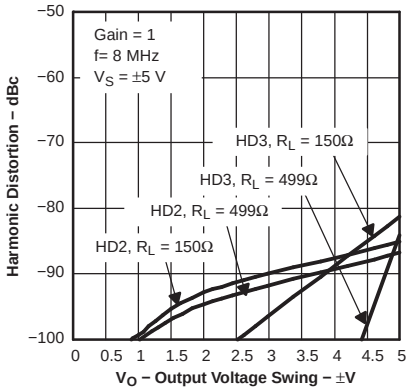


Figure 11.

HARMONIC DISTORTION vs OUTPUT VOLTAGE SWING

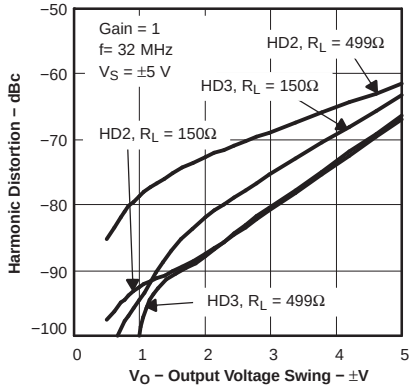


Figure 12.

HARMONIC DISTORTION vs OUTPUT VOLTAGE SWING

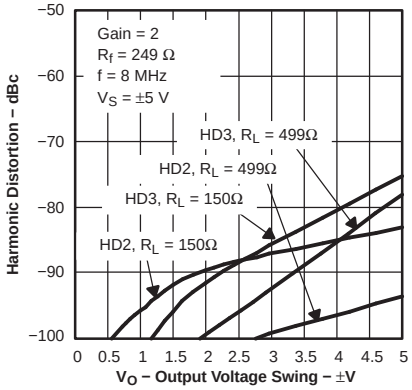


Figure 13.

HARMONIC DISTORTION vs OUTPUT VOLTAGE SWING

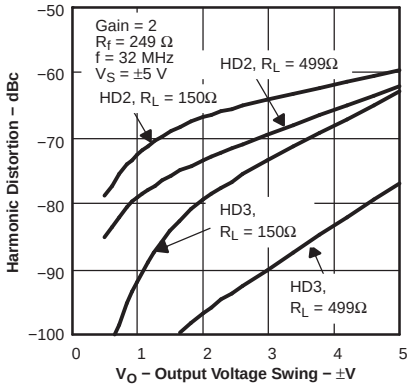


Figure 14.

THIRD-ORDER INTERMODULATION DISTORTION vs FREQUENCY

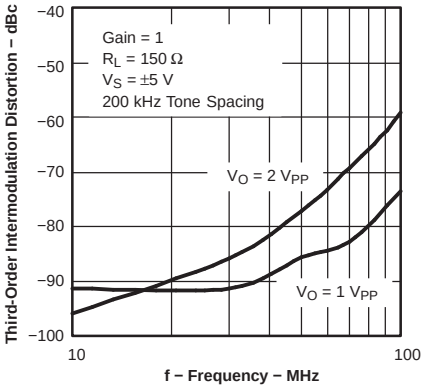


Figure 15.

THIRD-ORDER INTERMODULATION DISTORTION vs FREQUENCY

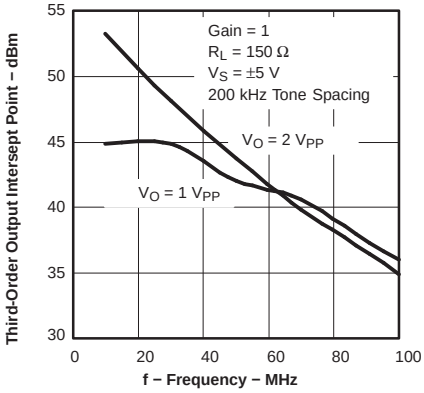


Figure 16.

THIRD-ORDER INTERMODULATION DISTORTION vs FREQUENCY

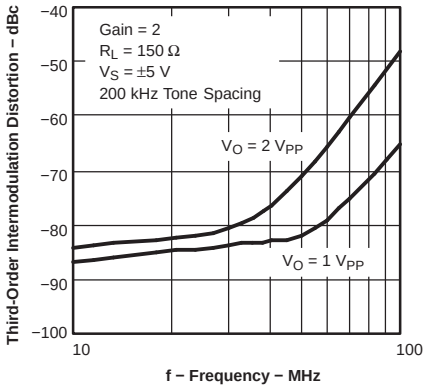


Figure 17.

THIRD-ORDER OUTPUT INTERCEPT POINT vs FREQUENCY

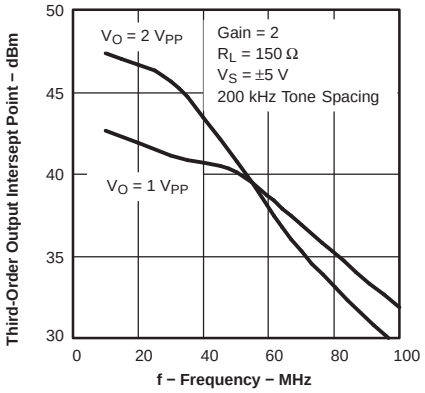


Figure 18.

VOLTAGE AND CURRENT NOISE vs FREQUENCY

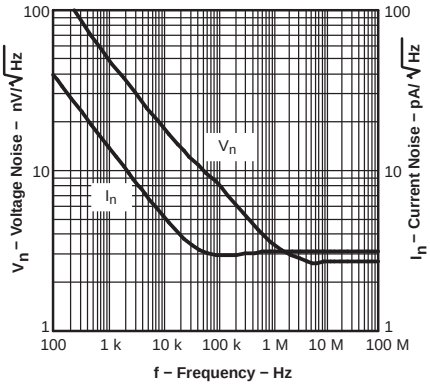


Figure 19.

TYPICAL CHARACTERISTICS: ±5 V (continued)

DIFFERENTIAL GAIN vs NUMBER OF LOADS

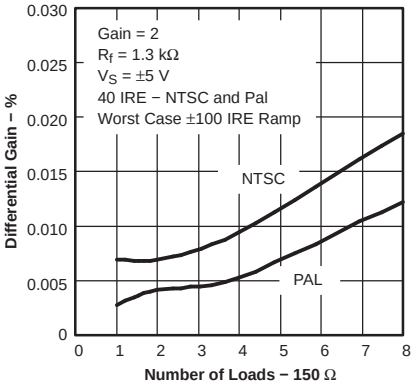


Figure 20.

DIFFERENTIAL PHASE vs NUMBER OF LOADS

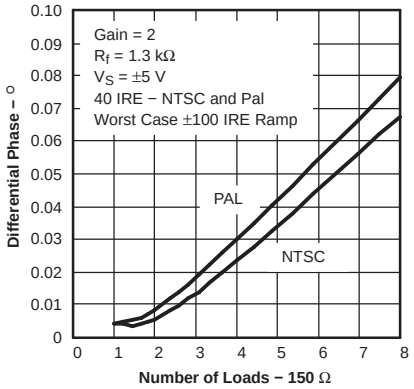


Figure 21.

SETTLING TIME

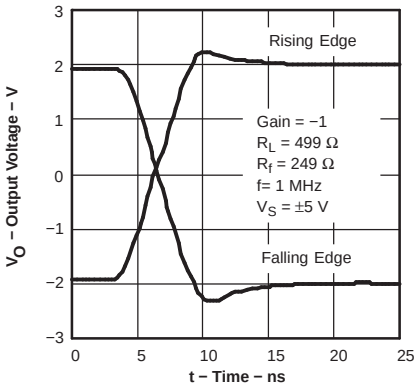


Figure 22.

QUIESCENT CURRENT vs SUPPLY VOLTAGE

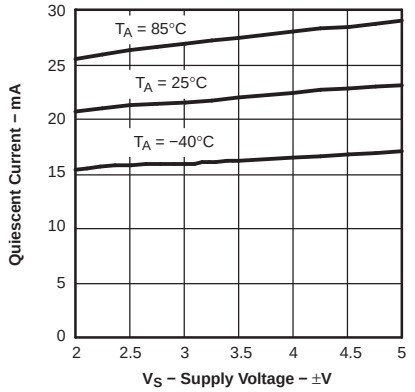


Figure 23.

OUTPUT VOLTAGE vs LOAD RESISTANCE

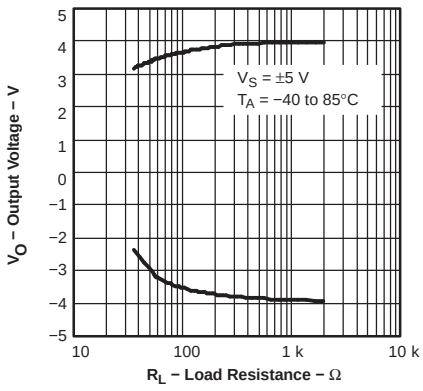


Figure 24.

FREQUENCY RESPONSE vs CAPACITIVE LOAD

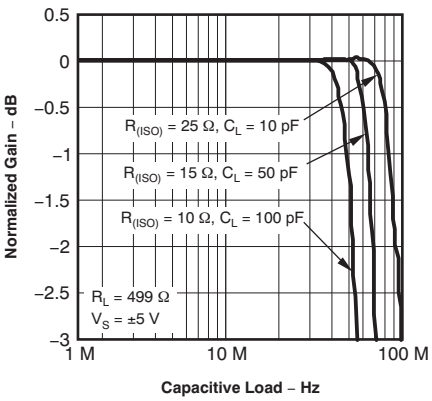


Figure 25.

OPEN-LOOP GAIN AND PHASE vs FREQUENCY

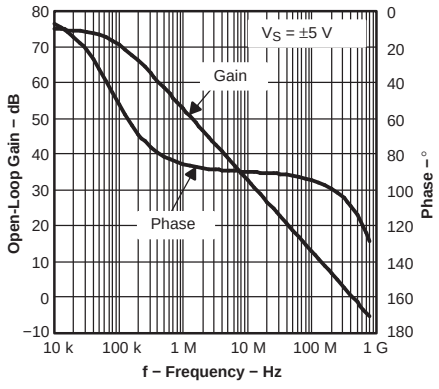


Figure 26.

OPEN-LOOP GAIN vs SUPPLY VOLTAGE

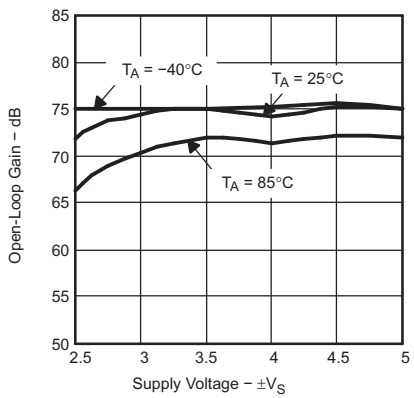


Figure 27.

REJECTION RATIOS vs FREQUENCY

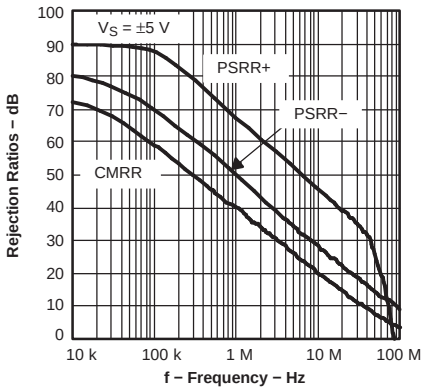


Figure 28.

TYPICAL CHARACTERISTICS: ±5 V (continued)

REJECTION RATIOS vs FREQUENCY

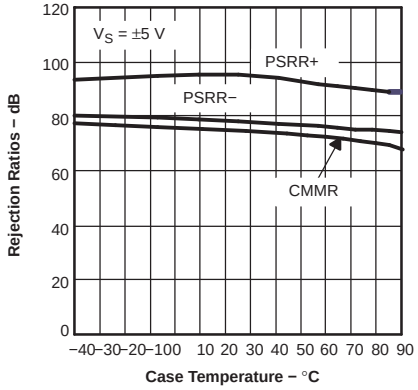


Figure 29.

COMMON-MODE REJECTION RATIOS vs INPUT COMMON-MODE RANGE

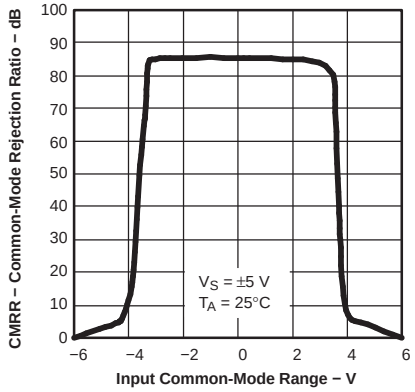


Figure 30.

INPUT OFFSET VOLTAGE vs CASE TEMPERATURE

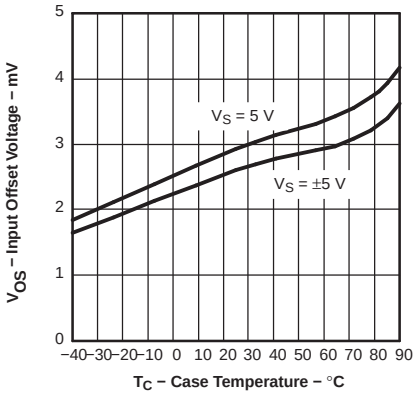


Figure 31.

INPUT BIAS AND OFFSET CURRENT vs CASE TEMPERATURE

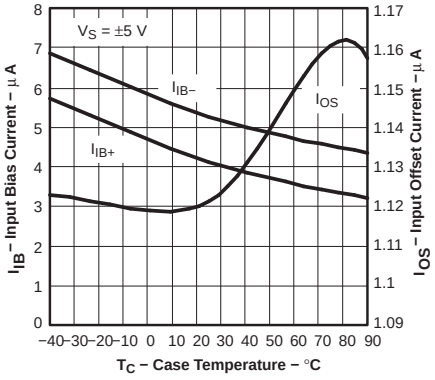


Figure 32.

SMALL-SIGNAL TRANSIENT RESPONSE

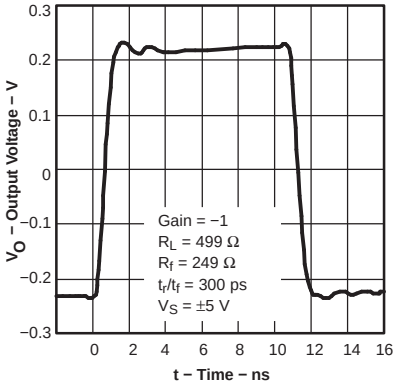


Figure 33.

LARGE-SIGNAL TRANSIENT RESPONSE

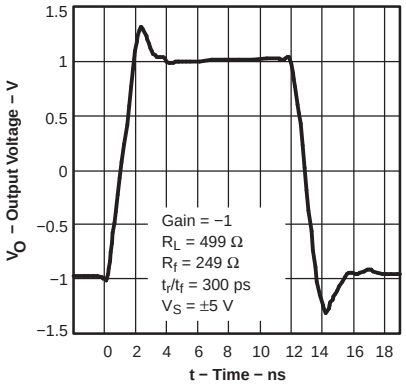


Figure 34.

OVERDRIVE RECOVERY

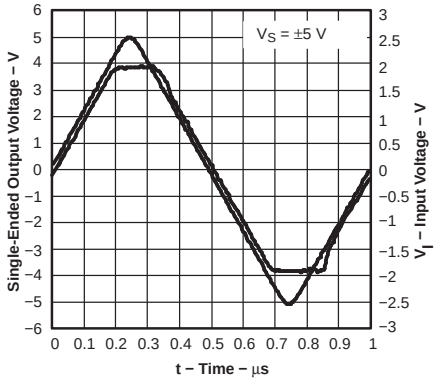


Figure 35.

CLOSED-LOOP OUTPUT IMPEDANCE vs FREQUENCY

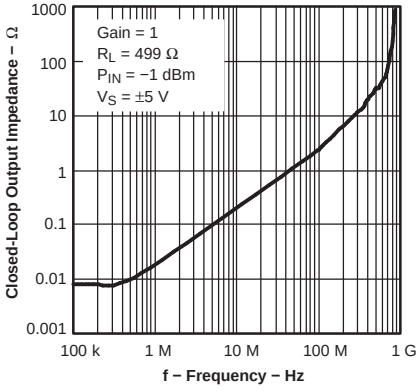


Figure 36.

POWER-DOWN QUIESCENT CURRENT vs SUPPLY VOLTAGE

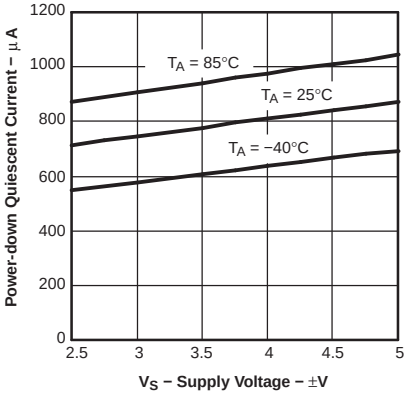


Figure 37.

TYPICAL CHARACTERISTICS: ±5 V (continued)

POWER-DOWN OUTPUT IMPEDANCE vs FREQUENCY

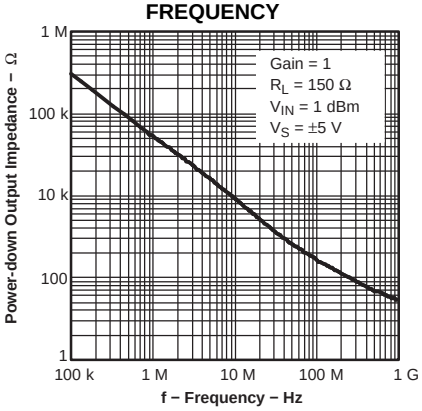


Figure 38.

TYPICAL CHARACTERISTICS: 5 V

SMALL-SIGNAL UNIT GAIN FREQUENCY RESPONSE

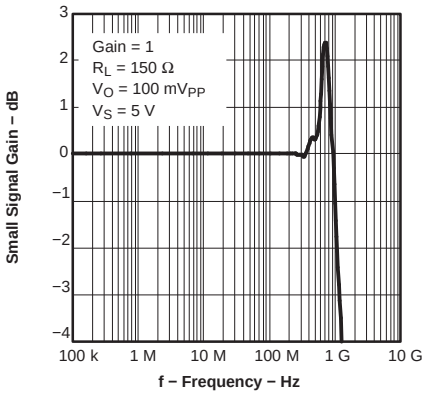


Figure 40.

SMALL-SIGNAL UNIT GAIN FREQUENCY RESPONSE

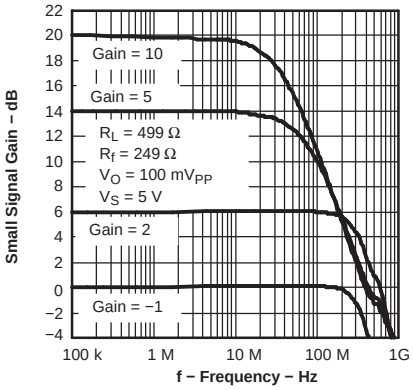


Figure 41.

0.1-dB GAIN FLTANESS FREQUENCY RESPONSE

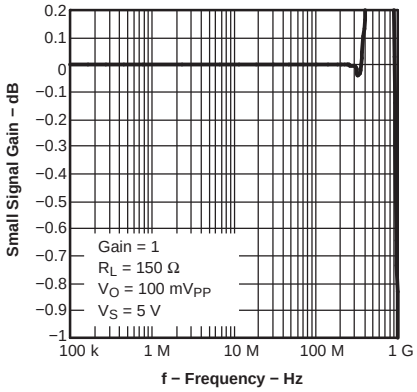


Figure 42.

LARGE-SIGNAL FREQUENCY RESPONSE

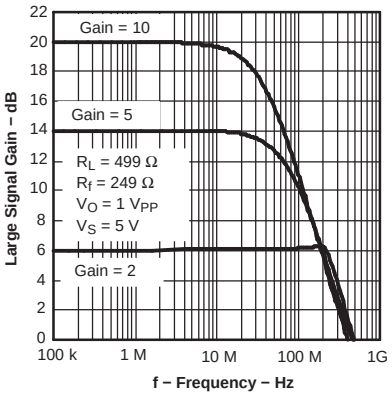


Figure 43.

SLEW RATE vs FREQUENCY

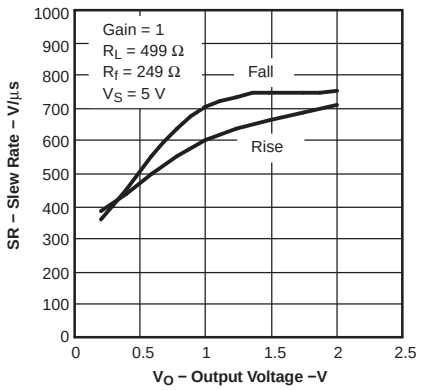


Figure 44.

HARMONIC DISTORTION DISTORTION vs FREQUENCY

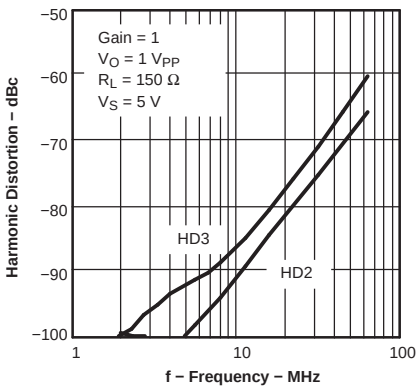


Figure 45.

TYPICAL CHARACTERISTICS: 5 V (continued)

HARMONIC DISTORTION vs FREQUENCY

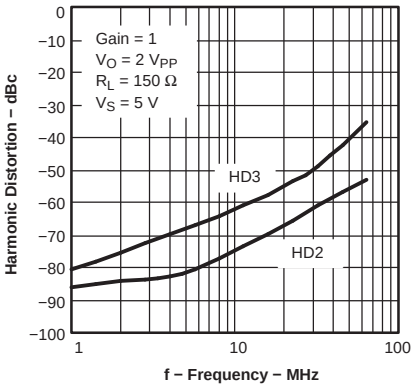


Figure 46.

HARMONIC DISTORTION vs FREQUENCY

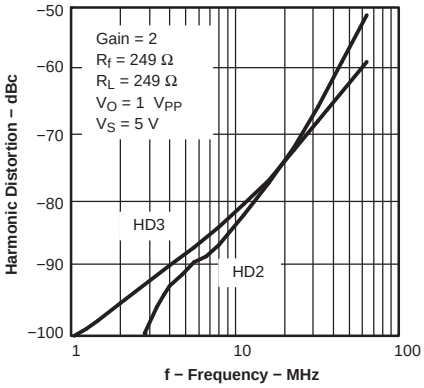


Figure 47.

HARMONIC DISTORTION vs FREQUENCY

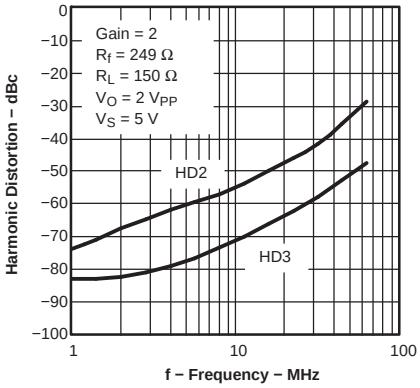


Figure 48.

HARMONIC DISTORTION vs OUTPUT VOLTAGE SWING

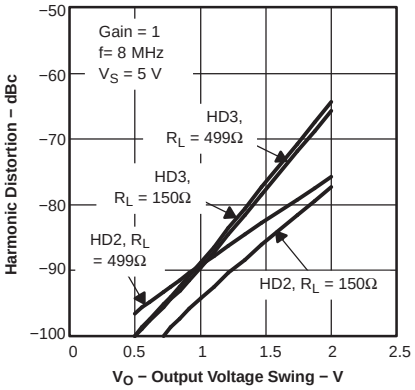


Figure 49.

HARMONIC DISTORTION vs OUTPUT VOLTAGE SWING

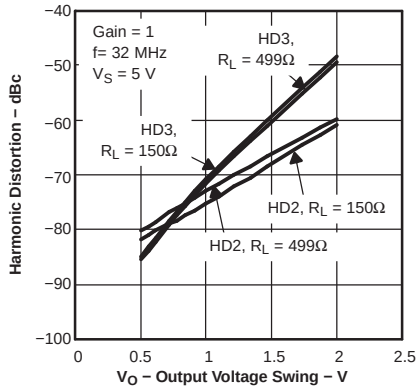


Figure 50.

HARMONIC DISTORTION vs OUTPUT VOLTAGE SWING

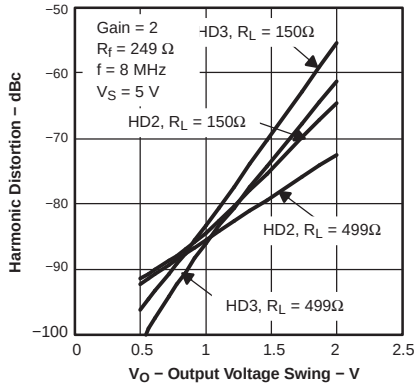


Figure 51.

HARMONIC DISTORTION vs OUTPUT VOLTAGE SWING

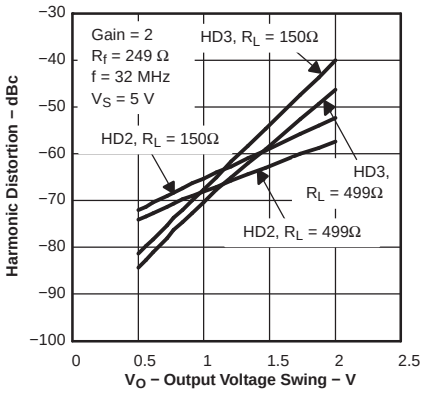


Figure 52.

THIRD-ORDER INTERMODULATION DISTORTION vs FREQUENCY

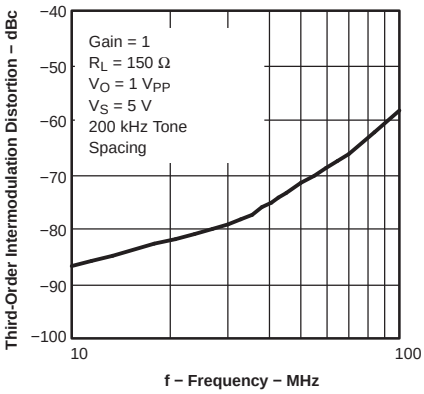


Figure 53.

THIRD-ORDER OUTPUT INTERCEPT POINT vs FREQUENCY

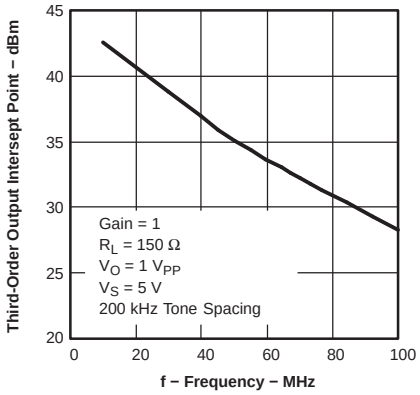


Figure 54.

TYPICAL CHARACTERISTICS: 5 V (continued)

THIRD-ORDER INTERMODULATION DISTORTION vs FREQUENCY

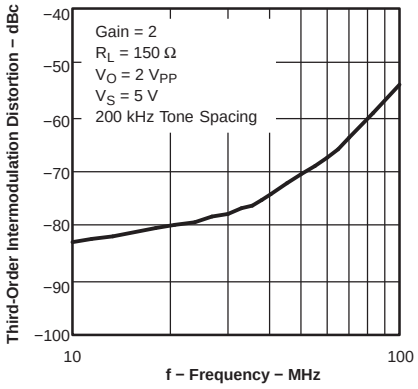


Figure 55.

THIRD-ORDER OUTPUT INTERCEPT POINT vs FREQUENCY

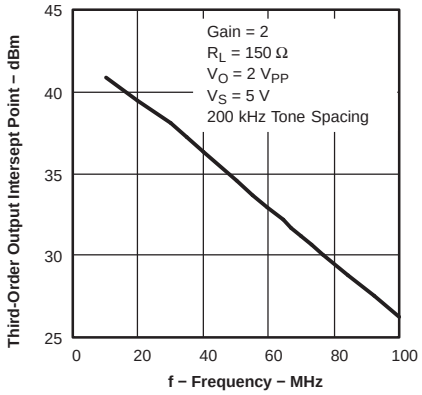


Figure 56.

VOLTAGE AND CURRENT NOISE vs FREQUENCY

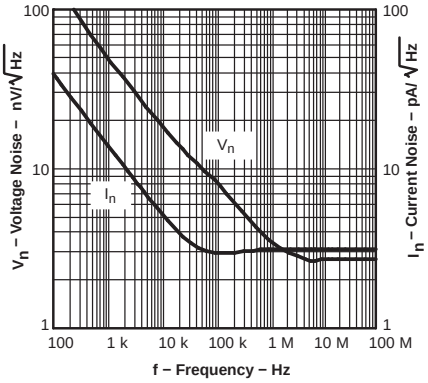


Figure 57.

SETTLING TIME

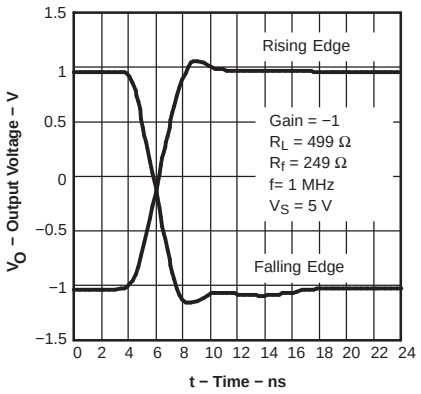


Figure 58.

QUIESCENT CURRENT vs SUPPLY VOLTAGE

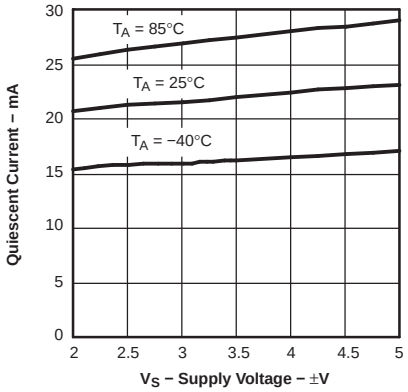


Figure 59.

OUTPUT VOLTAGE vs LOAD RESISTANCE

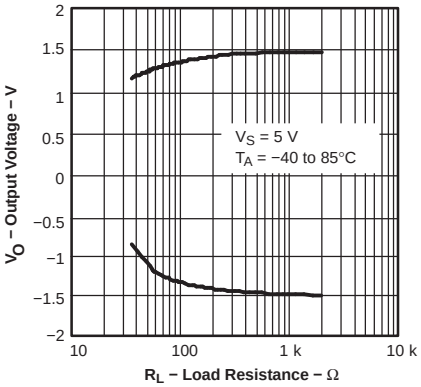


Figure 60.

FREQUENCY RESPONSE vs CAPACITIVE LOAD

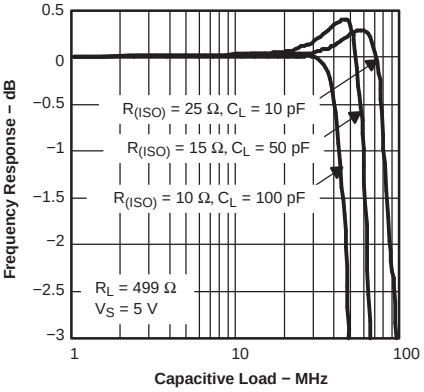


Figure 61.

OPEN-LOOP GAIN AND PHASE vs FREQUENCY

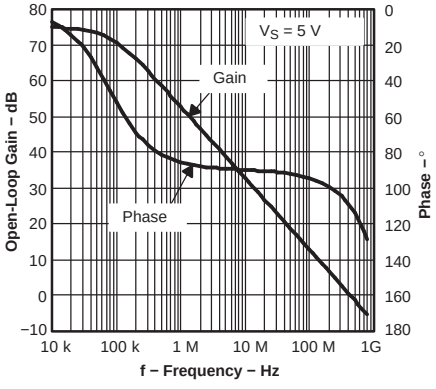


Figure 62.

OPEN-LOOP GAIN vs CASE TEMPERATURE

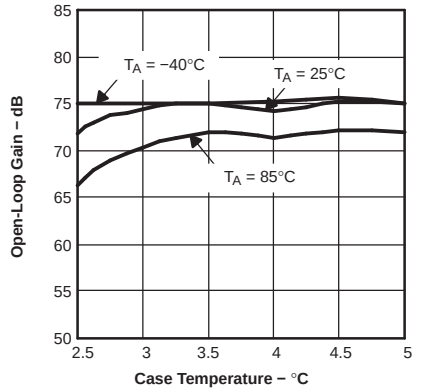


Figure 63.

TYPICAL CHARACTERISTICS: 5 V (continued)

REJECTION RATIOS vs FREQUENCY

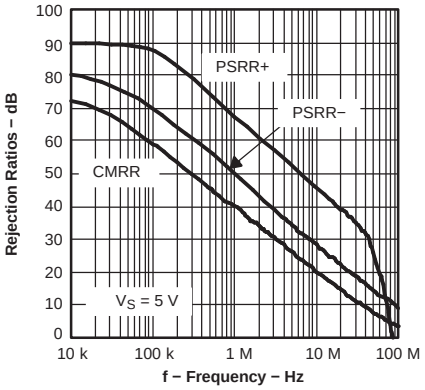


Figure 64.

REJECTION RATIOS vs CASE TEMPERATURE

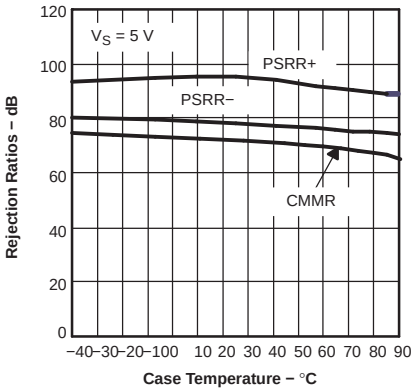


Figure 65.

COMMON-MODE REJECTION RATIO vs INPUT COMMON-MODE RANGE

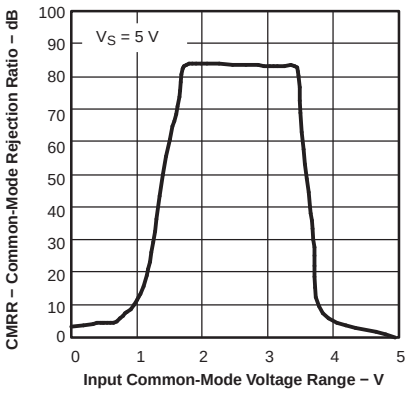


Figure 66.

INPUT OFFSET VOLTAGE vs CASE TEMPERATURE

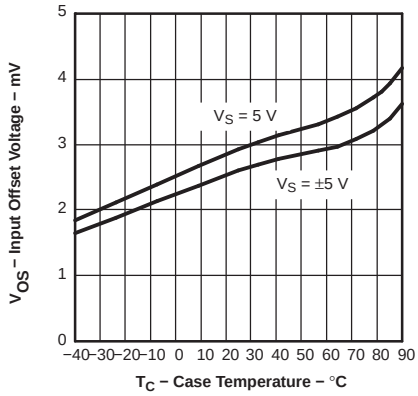


Figure 67.

INPUT BIAS AND OFFSET CURRENT vs CASE TEMPERATURE

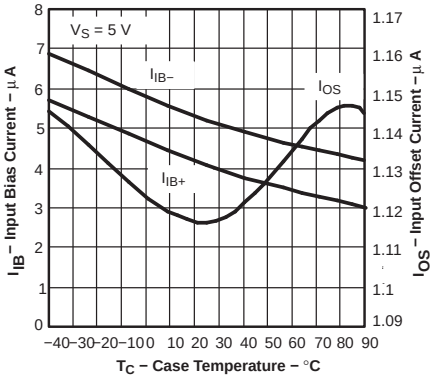


Figure 68.

SMALL-SIGNAL TRANSIENT RESPONSE

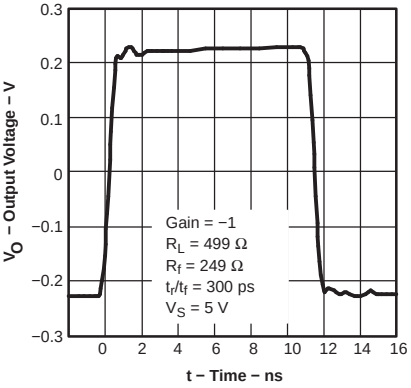


Figure 69.

LARGE-SIGNAL TRANSIENT RESPONSE

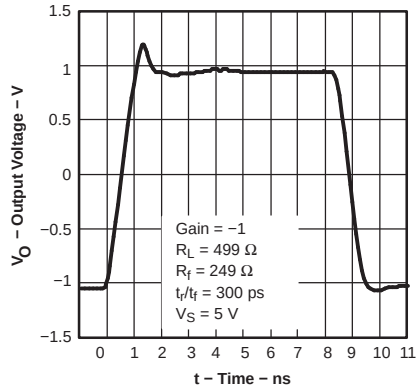


Figure 70.

OVERDRIVE RECOVERY

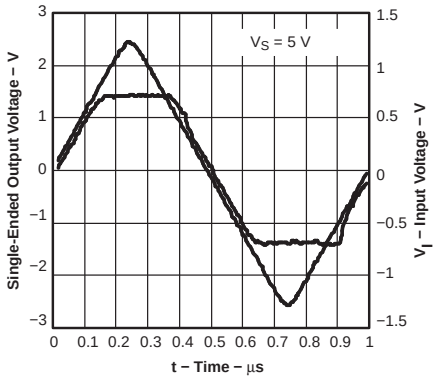


Figure 71.

CLOSED-LOOP OUTPUT IMPEDANCE vs FREQUENCY

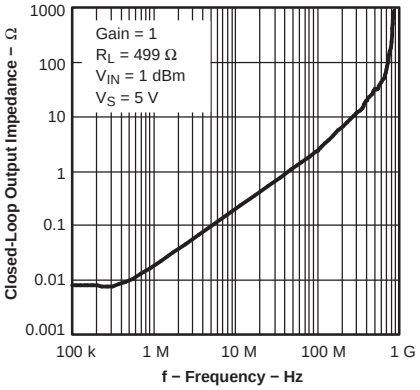


Figure 72.

TYPICAL CHARACTERISTICS: 5 V (continued)

POWER-DOWN QUIESCENT CURRENT vs SUPPLY VOLTAGE

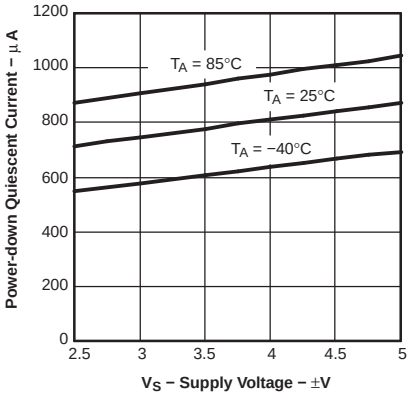


Figure 73.

POWER-DOWN OUTPUT IMPEDANCE vs FREQUENCY

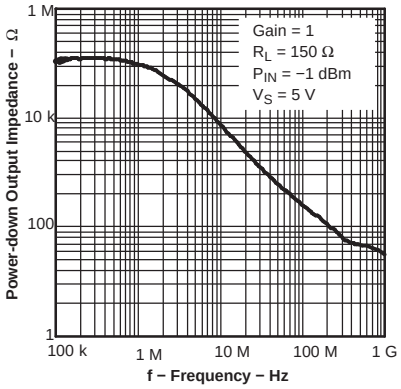


Figure 74.

TURN-ON AND TURN-OFF TIME vs DELAY TIME

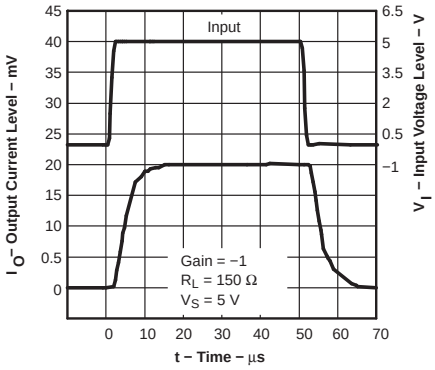


Figure 75.

APPLICATION INFORMATION

MAXIMUM DIE TEMPERATURE TO PREVENT OSCILLATION

The THS4271 may have low-level oscillation when the die temperature (also called *junction temperature*) exceeds +60°C and is not recommended for new designs.

The oscillation is a result of the internal design of the bias circuit, and external configuration is not expected to mitigate or reduce the problem. This problem occurs randomly because of normal process variations and normal testing cannot identify problem units.

The die temperature depends on the power dissipation and the thermal resistance of the device.

The die temperature can be approximated with the following formula:

$$\text{Die Temperature} = P_{DISS} \times \theta_{JA} + T_A$$

Where:

$$P_{DISS} = (V_{S+} - V_{S-}) \times (I_Q + I_{LOAD}) - (V_{OUT} \times I_{LOAD})$$

Table 1 shows the estimated the maximum ambient temperature (T_A max) in degrees Celsius for each package option of the THS4271 using the thermal dissipation rating given in the Dissipation Ratings table for a JEDEC standard High-K test PCB. For each case shown, R_L = 499 Ω to ground and the quiescent current = 27 mA (the maximum over the 0°C to +70°C temperature range). The last entry for each package option (shaded cells) lists the worst-case scenario where the power supply is single-supply 10 V and ground and the output voltage is 5 V DC.

Table 1. Estimated Maximum Ambient Temperature Per Package Option

PACKAGE DEVICE	V_{S+}	V_{S-}	V_{OUT}	θ_{JA}	T_A max
PowerPad™ MSOP	5 V	–5 V	0 V	58.4°C/W	44.2°C
THS4271DGN			2 V_{PP}		43.5°C
THS4271DGNR			4 V_{PP}		42.8°C
			6 V_{PP}		42.3°C
			8 V_{PP}		41.9°C
Worst Case	10 V	0 V	5 DC		41.3°C

HIGH-SPEED OPERATIONAL AMPLIFIERS

The THS4271 operational amplifier sets new performance levels, combining low distortion, high slew rates, low noise, and a unity-gain bandwidth in excess of 1 GHz. To achieve the full performance of the amplifier, careful attention must be paid to printed-circuit board (PCB) layout and component selection.

Applications Section Contents

- Wideband, Noninverting Operation
- Wideband, Inverting Gain Operation
- Single-Supply Operation
- Saving Power with Power-Down Functionality and Setting Threshold Levels with the Reference Pin
- Power Supply Decoupling Techniques and Recommendations
- Using the THS4271 as a DAC Output Buffer
- Driving an ADC With the THS4271
- Active Filtering With the THS4271
- Building a Low-Noise Receiver with the THS4271
- Linearity: Definitions, Terminology, Circuit Techniques and Design Tradeoffs
- An Abbreviated Analysis of Noise in Amplifiers
- Driving Capacitive Loads
- Printed Circuit Board Layout Techniques for Optimal Performance
- Power Dissipation and Thermal Considerations
- Performance vs Package Options
- Evaluation Fixtures, Spice Models, and Applications Support
- Additional Reference Material
- Mechanical Package Drawings

WIDEBAND, NONINVERTING OPERATION

The THS4271 is a unity gain stable, 1.4-GHz voltage-feedback operational amplifier, with and without power-down capability, designed to operate from a single 5-V to 15-V power supply.

Figure 76 is the noninverting gain configuration of 2 V/V used to demonstrate the typical performance curves. Most of the curves were characterized using signal sources with 50-Ω source impedance, and with measurement equipment presenting a 50-Ω load impedance. In Figure 76, the 49.9-Ω shunt resistor at the V_{IN} terminal matches the source impedance of the test generator. The total 499-Ω load at the output, combined with the 498-Ω total feedback network load, presents the THS4271 with an effective output load of 249 Ω for the circuit of Figure 76.

Voltage feedback amplifiers, unlike current feedback designs, can use a wide range of resistors values to set their gain with minimal impact on their stability and frequency response. Larger-valued resistors decrease the loading effect of the feedback network on the output of the amplifier, but this enhancement comes at the expense of additional noise and potentially lower bandwidth. Feedback resistor values between 249 Ω and 1 kΩ are recommended for most situations.

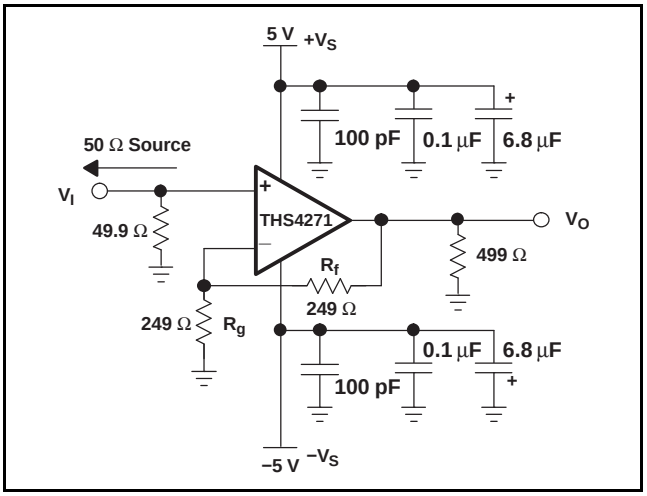


Figure 76. Wideband, Noninverting Gain Configuration

WIDEBAND, INVERTING GAIN OPERATION

Since the THS4271 is a general-purpose, wideband voltage-feedback amplifiers, several familiar operational amplifier applications circuits are available to the designer. Figure 77 shows a typical inverting configuration where the input and output impedances and noise gain from Figure 76 are retained in an inverting circuit configuration. Inverting operation is one of the more common requirements and offers several performance benefits. The inverting configuration shows improved slew rates and distortion due to the pseudo-static voltage maintained on the inverting input.

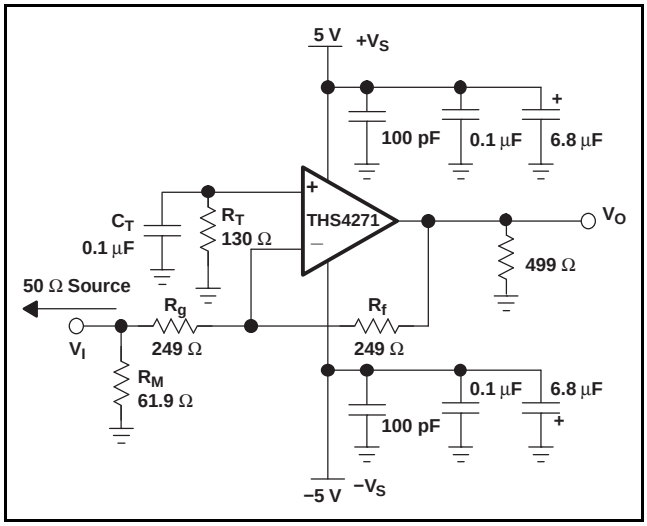


Figure 77. Wideband, Inverting Gain Configuration

In the inverting configuration, some key design considerations must be noted. One is that the gain resistor (R_g) becomes part of the signal channel input impedance. If the input impedance matching is desired (which is beneficial whenever the signal is coupled through a cable, twisted pair, long PCB trace, or other transmission line conductors), R_g may be set equal to the required termination value and R_f adjusted to give the desired gain. However, care must be taken when dealing with low inverting gains, as the resulting feedback resistor value can present a significant load to the amplifier output. For an inverting gain of 2, setting R_g to 49.9 Ω for input matching eliminates the need for R_M but requires a 100-Ω feedback resistor. This has an advantage of the noise gain becoming equal to 2 for a 50-Ω source impedance—the same as the noninverting circuit in Figure 76. However, the amplifier output now sees the 100-Ω feedback resistor in parallel with the external load. To eliminate this excessive loading, it is preferable to increase both R_g and R_f, values, as shown in Figure 77, and then achieve the input matching impedance with a third resistor (R_M) to ground. The total input impedance becomes the parallel combination of R_g and R_M.

The next major consideration is that the signal source impedance becomes part of the noise gain equation and hence influences the bandwidth. For example, the R_M value combines in parallel with the external 50-Ω source impedance (at high frequencies), yielding an effective source impedance of 50 Ω || 61.9Ω = 27.7 Ω. This impedance is then added in series with R_g for calculating the noise gain. The result is 1.9 for Figure 77, as opposed to the 1.8 if R_M is eliminated. The bandwidth is lower for the gain of –2 circuit, Figure 77 (NG = +1.9), than for the gain of +2 circuit in Figure 76.

The last major consideration in inverting amplifier design is setting the bias current cancellation resistor on the noninverting input. If the resistance is set equal to the total dc resistance looking out of the inverting terminal, the output dc error, due to the input bias currents, is reduced to (input offset current) multiplied by R_f in Figure 77, the dc source impedance looking out of the inverting terminal is 249 Ω || (249Ω + 27.7 Ω) = 130 Ω. To reduce the additional high-frequency noise introduced by the resistor at the noninverting input, and power-supply feedback, R_T is bypassed with a capacitor to ground.

SINGLE-SUPPLY OPERATION

The THS4271 is designed to operate from a single 5-V to 15-V power supply. When operating from a single power supply, care must be taken to ensure the input signal and amplifier are biased appropriately to allow for the maximum output voltage swing. The circuits shown in Figure 78 demonstrate methods to configure an amplifier in a manner conducive for single-supply operation.

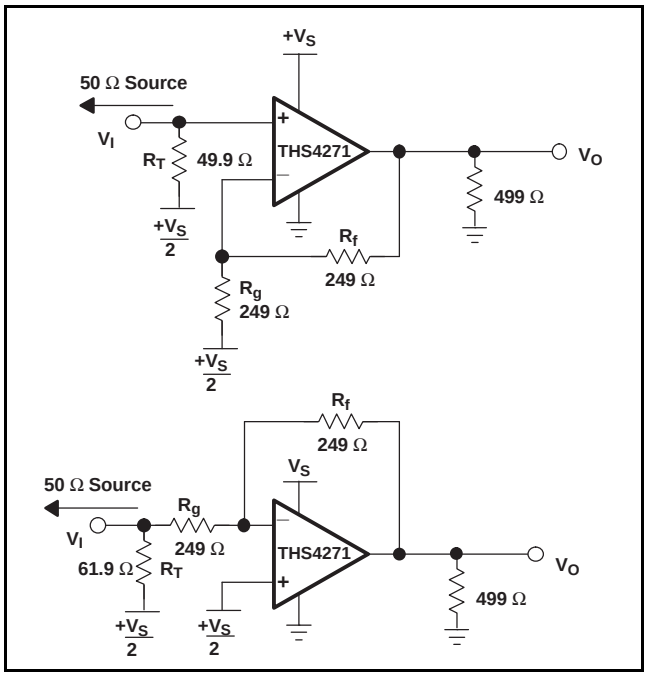


Figure 78. DC-Coupled Single-Supply Operation

APPLICATION CIRCUITS

Driving an Analog-to-Digital Converter With the THS4271

The THS4271 can be used to drive high-performance analog-to-digital converters. Two example circuits are presented below.

The first circuit uses a wideband transformer to convert a single-ended input signal into a differential signal. The differential signal is then amplified and filtered by two THS4271 amplifiers. This circuit provides low intermodulation distortion, suppressed even-order distortion, 14 dB of voltage gain, a 50-Ω input impedance, and a single-pole filter at 100 MHz. For applications without signal content at dc, this method of driving ADCs can be very useful. Where dc information content is required, the THS4500 family of fully differential amplifiers may be applicable.

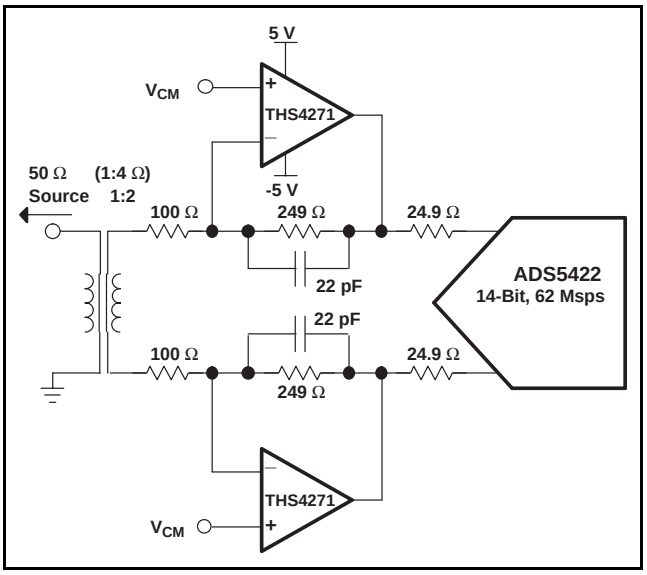
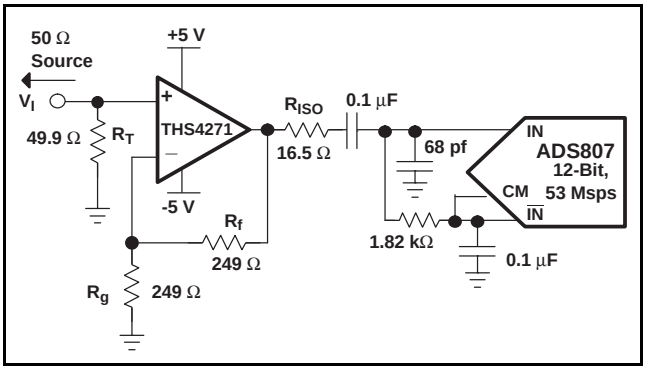


Figure 79. A Linear, Low-Noise, High-Gain ADC Preamplifier

The second circuit depicts single-ended ADC drive. While not recommended for optimum performance using converters with differential inputs, satisfactory performance can sometimes be achieved with single-ended input drive. An example circuit is shown here for reference.



For best performance, high-speed ADCs should be driven differentially. See the THS4500 family of devices for more information.

Figure 80. Driving an ADC With a Single-Ended Input

Using the THS4271 as a DAC Output Buffer

Two example circuits are presented here showing the THS4271 buffering the output of a digital-to-analog converter. The first circuit performs a differential to single-ended conversion with the THS4271 configured as a difference amplifier. The difference amplifier can double as the termination mechanism for the DAC outputs as well.

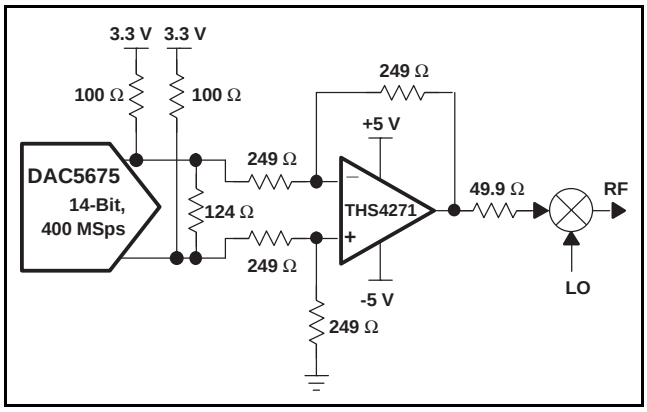


Figure 81. Differential to Single-Ended Conversion of a High-Speed DAC Output

For cases where a differential signaling path is desirable, a pair of THS4271 amplifiers can be used as output buffers. The circuit depicts differential drive into a mixer IF inputs, coupled with additional signal gain and filtering.

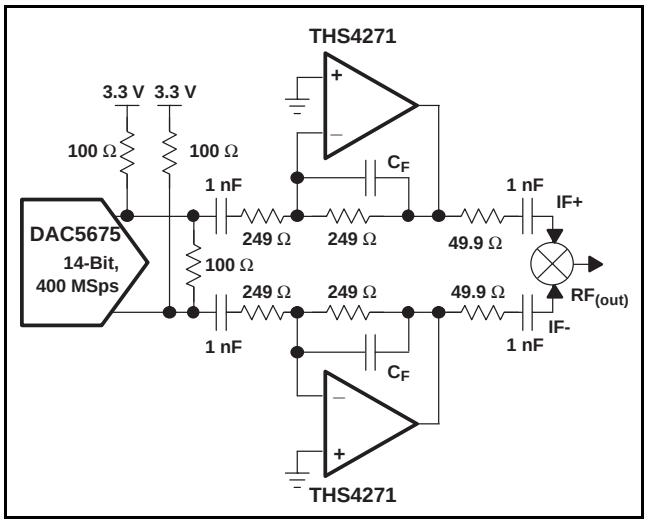


Figure 82. Differential Mixer Drive Circuit Using the DAC5675 and the THS4271

Active Filtering With the THS4271

High-frequency active filtering with the THS4271 is achievable due to the amplifier high slew-rate, wide bandwidth, and voltage-feedback architecture. Several options are available for high-pass, low-pass, bandpass, and bandstop filters of varying orders. A simple two-pole low pass filter is presented here as an example, with two poles at 100 MHz.

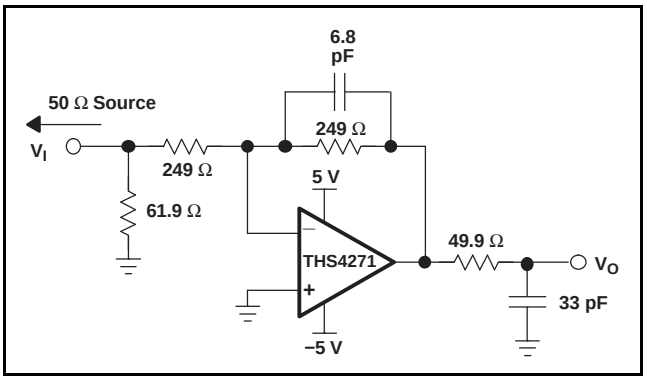


Figure 83. A Two-Pole Active Filter With Two Poles Between 90 MHz and 100 MHz

A Low-Noise Receiver With the THS4271

A combination of two THS4271 amplifiers can create a high-speed, low-distortion, low-noise differential receiver circuit as depicted in Figure 84. With both amplifiers operating in the noninverting mode of operation, the circuit presents a high load impedance to the source. The designer has the option of controlling the impedance through termination resistors if a matched termination impedance is desired.

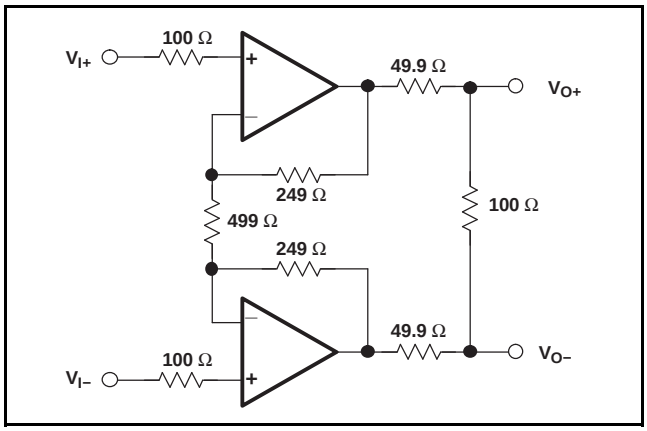


Figure 84. A High Input Impedance, Low-Noise, Differential Receiver

A modification on this circuit to include a difference amplifier turns this circuit into a high-speed instrumentation amplifier, as shown in Figure 85. Equation 1 calculates the output voltage for this circuit.

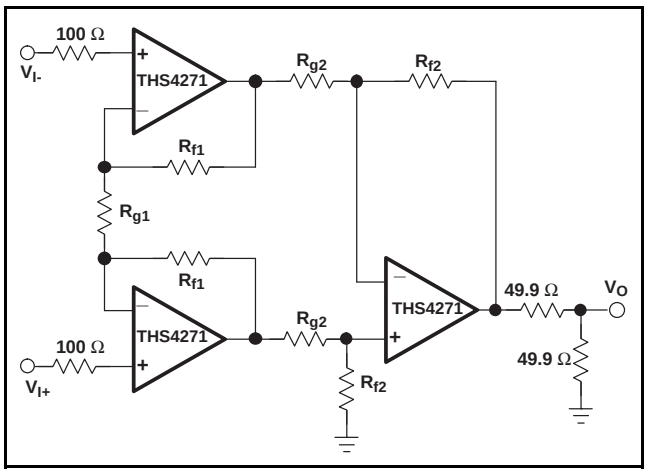


Figure 85. A High-Speed Instrumentation Amplifier

$$V_O = \frac{1}{2}\left(1 + \frac{2R_{f1}}{R_{g1}}\right)(V_{i+} - V_{i-})\left(\frac{R_{f2}}{R_{g2}}\right) \quad (1)$$

THEORY AND GUIDELINES

Distortion Performance

The THS4271 provides excellent distortion performance into a 150-Ω load. Relative to alternative solutions, it provides exceptional performance into lighter loads, as well as exceptional performance on a single 5-V supply. Generally, until the fundamental signal reaches very high frequency or power levels, the second harmonic dominates the total harmonic distortion with a negligible third harmonic component. Focusing then on the second harmonic, increasing the load impedance improves distortion directly. The total load includes the feedback network; in the noninverting configuration (Figure 76) this is the sum of R_f and R_g, while in the inverting configuration (Figure 77), only R_f needs to be included in parallel with the actual load.

LINEARITY: DEFINITIONS, TERMINOLOGY, CIRCUIT TECHNIQUES, AND DESIGN TRADEOFFS

The THS4271 features excellent distortion performance for monolithic operational amplifiers. This section focuses on the fundamentals of distortion, circuit techniques for reducing nonlinearity, and methods for equating distortion of operational amplifiers to desired linearity specifications in RF receiver chains.

Amplifiers are generally thought of as *linear* devices. The output of an amplifier is a linearly-scaled version of the input signal applied to it. However, amplifier transfer functions are nonlinear. Minimizing amplifier nonlinearity is a primary design goal in many applications.

Intercept points are specifications long used as key design criteria in the RF communications world as a metric for the intermodulation distortion performance of a device in the signal chain (e.g., amplifiers, mixers, etc.). Use of the intercept point, rather than strictly the intermodulation distortion, allows simpler system-level calculations. Intercept points, like noise figures, can be easily cascaded back and forth through a signal chain to determine the overall receiver chain intermodulation distortion performance. The relationship between intermodulation distortion and intercept point is depicted in Figure 86 and Figure 87.

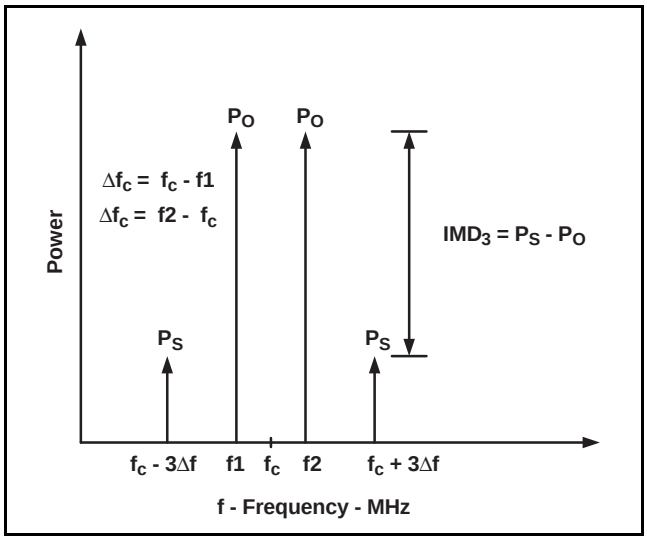


Figure 86.

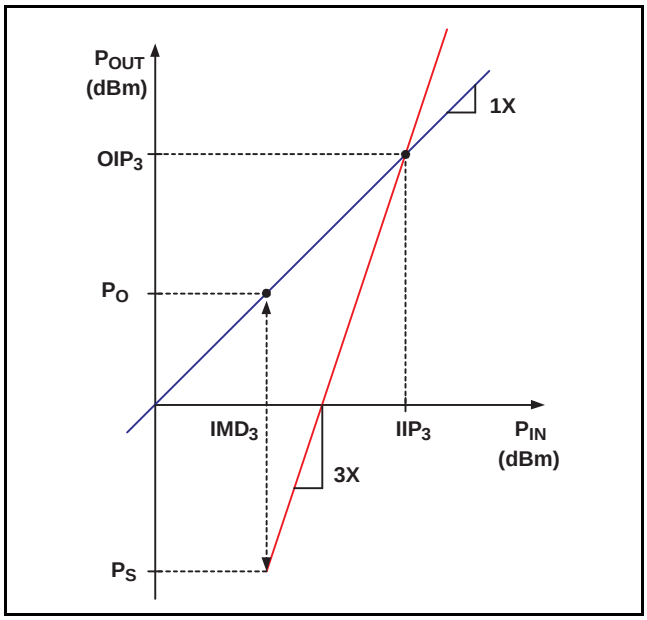


Figure 87.

Due to the intercept point ease of use in system level calculations for receiver chains, it has become the specification of choice for guiding distortion-related design decisions. Traditionally, these systems use primarily class-A, single-ended RF amplifiers as gain blocks. These RF amplifiers are typically designed to operate in a 50-Ω environment. Giving intercept points in dBm, implies an associated impedance (50 Ω).

However, with an operational amplifier, the output does not require termination as an RF amplifier would. Because closed-loop amplifiers deliver signals to their outputs regardless of the impedance present, it is important to comprehend this when evaluating the intercept point of an operational amplifier. The THS4271 yields optimum distortion performance when loaded with 150 Ω to 1 kΩ, very similar to the input impedance of an analog-to-digital converter over its input frequency band.

As a result, terminating the input of the ADC to 50Ω can actually be detrimental to systems performance.

The discontinuity between open-loop, class-A amplifiers and closed-loop, class-AB amplifiers becomes apparent when comparing the intercept points of the two types of devices. Equation 2 and Equation 3 give the definition of an intercept point, relative to the intermodulation distortion.

$$OIP_3 = P_O + \left(\frac{|IMD_3|}{2}\right) \text{ where} \quad (2)$$

$$P_O = 10 \log\left(\frac{V_P^2}{2R_L \times 0.001}\right)$$

NOTE: P_O is the output power of a single tone, R_L is the load resistance, and V_P is the peak voltage for a single tone. (3)

NOISE ANALYSIS

High slew rate, unity gain stable, voltage-feedback operational amplifiers usually achieve the slew rate at the expense of a higher input noise voltage. The 3-nV/√Hz input voltage noise for the THS4271 is, however, much lower than comparable amplifiers. The input-referred voltage noise, and the two input-referred current noise terms (3 pA/√Hz), combine to give low output noise under a wide variety of operating conditions. Figure 88 shows the amplifier noise analysis model with all the noise terms included. In this model, all noise terms are taken to be noise voltage or current density terms in either nV/√Hz or pA/√Hz.

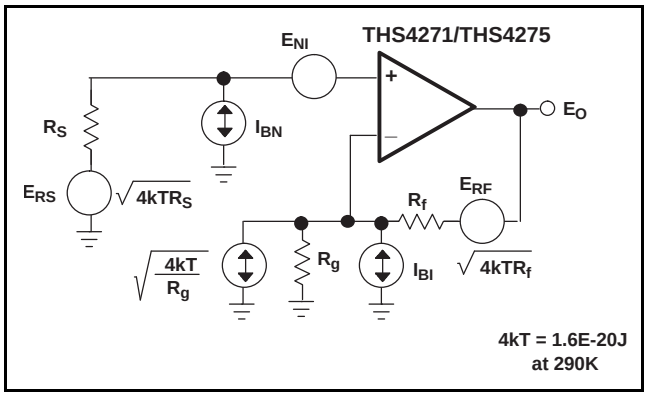


Figure 88. Noise Analysis Model

The total output spot noise voltage can be computed as the square of all square output noise voltage contributors. Equation 4 shows the general form for the output noise voltage using the terms shown in Figure 88:

$$E_O = \sqrt{\left(E_{NI}^2 + \left(I_{BN}R_S\right)^2 + 4kTR_S\right)NG^2 + \left(I_{BI}R_f\right)^2 + 4kTR_fNG} \quad (4)$$

Dividing this expression by the noise gain [NG=(1+ R_f/R_g)] gives the equivalent input-referred spot noise voltage at the noninverting input, as shown in Equation 5:

$$E_O = \sqrt{E_{NI}^2 + \left(I_{BN}R_S\right)^2 + 4kTR_S + \left(\frac{I_{BI}R_f}{NG}\right)^2 + \frac{4kTR_f}{NG}} \quad (5)$$

Evaluation of these two equations for the circuit and component values shown in Figure 76 will give a total output spot noise voltage of 12.2 nV/√Hz and a total equivalent input spot noise voltage of 6.2 nV/√Hz. This includes the noise added by the resistors. This total input-referred spot noise voltage is not much higher than the 3-nV/√Hz specification for the amplifier voltage noise alone.

Driving Capacitive Loads

One of the most demanding, and yet very common, load conditions for an op amp is capacitive loading. Often, the capacitive load is the input of an A/D converter, including additional external capacitance, which may be recommended to improve A/D linearity. A high-speed, high open-loop gain amplifier like the THS4271 can be very susceptible to decreased stability and closed-loop response peaking when a capacitive load is placed directly on the output pin. When the amplifier open-loop output resistance is considered, this capacitive load introduces an additional pole in the signal path that can decrease the phase margin. When the primary considerations are frequency response flatness, pulse response fidelity, or distortion, the simplest and most effective solution is to isolate the capacitive load from the feedback loop by inserting a series isolation resistor between the amplifier output and the capacitive load. This does not eliminate the pole from the loop response, but rather shifts it and adds a zero at a higher frequency. The additional zero acts to cancel the phase lag from the capacitive load pole, thus increasing the phase margin and improving stability.

The *Typical Characteristics* show the recommended isolation resistor vs capacitive load and the resulting frequency response at the load. Parasitic capacitive loads greater than 2 pF can begin to degrade the performance of the THS4271. Long PCB traces, unmatched cables, and connections to multiple devices can easily cause this value to be exceeded. Always consider this effect carefully, and add the recommended series resistor as close as possible to the THS4271 output pin (see the *Board Layout Guidelines* section).

The criterion for setting this $R_{(ISO)}$ resistor is a maximum bandwidth, flat frequency response at the load. For a gain of +2, the frequency response at the output pin is already slightly peaked without the capacitive load, requiring relatively high values of $R_{(ISO)}$ to flatten the response at the load. Increasing the noise gain also reduces the peaking.

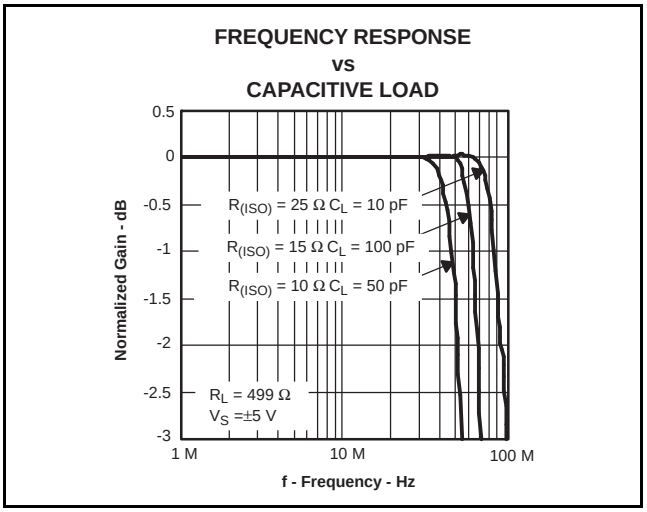


Figure 89. Isolation Resistor Diagram

BOARD LAYOUT GUIDELINES

Achieving optimum performance with a high-frequency amplifier like the THS4271 requires careful attention to board layout parasitics and external component types.

Recommendations that optimize performance include:

1. **Minimize parasitic capacitance to any ac ground for all of the signal I/O pins.** Parasitic capacitance on the output and inverting input pins can cause instability: on the noninverting input, it can react with the source impedance to cause unintentional band limiting. To reduce unwanted capacitance, a window around the signal I/O pins should be opened in all of the ground and power planes around those pins. Otherwise, ground and power planes should be unbroken elsewhere on the board.
2. **Minimize the distance (< 0.25") from the power supply pins to high frequency 0.1-μF de-coupling capacitors.** At the device pins, the ground and power plane layout should not be in close proximity to the signal I/O pins. Avoid narrow power and ground traces to minimize inductance between the pins and the decoupling capacitors. The power supply connections should always be decoupled with these capacitors. Larger (2.2-μF to 6.8-μF) decoupling capacitors, effective at lower frequency, should also be used on the main supply pins. These may be placed somewhat farther from the device and may be shared among several devices in the same area of the PCB.
3. **Careful selection and placement of external components preserves the high frequency performance of the THS4271.** Resistors should be a very low reactance type. Surface-mount resistors work best and allow a tighter overall layout. Metal-film and carbon composition, axially-leaded resistors can also provide good high frequency performance. Again, keep their leads and PC board trace length as short as possible. Never use wire-wound type resistors in a high frequency application. Since the output pin and inverting input pin are the most sensitive to parasitic capacitance, always position the feedback and series output resistor, if any, as close as possible to the output pin. Other network components, such as noninverting input-termination resistors, should also be placed close to the package. Where double-side component mounting is allowed, place the feedback resistor directly under the package on the other side of the board between the output and inverting input pins. Even with a low parasitic capacitance shunting the external resistors, excessively high resistor values can create significant time constants that can degrade performance. Good axial metal-film or surface-mount resistors have approximately 0.2 pF in shunt with the resistor. For resistor values > 2 kΩ, this parasitic capacitance can add a pole and/or a zero below 400-MHz that can effect circuit operation. Keep resistor values as low as possible, consistent with load driving considerations. A good starting point for design is to set the R_f to 249-Ω for low-gain, noninverting applications. Doing this automatically keeps the resistor noise terms low, and minimizes the effect of their parasitic capacitance.
4. **Connections to other wideband devices on the board may be made with short direct traces or through onboard transmission lines.** For short connections, consider the trace and the input to the next device as a lumped capacitive load. Relatively wide traces (50 mils to 100 mils) should be used, preferably with ground and power planes opened up around them. Estimate the total capacitive load and set R_{ISO} from the plot of recommended R_{ISO} vs capacitive load. Low parasitic capacitive loads (<4 pF) may not need an $R_{(ISO)}$, since the THS4271 is nominally compensated to operate with a 2-pF parasitic load. Higher parasitic capacitive loads without an $R_{(ISO)}$ are allowed as the signal gain increases (increasing the unloaded phase margin). If a long trace is required, and the 6-dB signal loss intrinsic to a doubly-terminated transmission line is acceptable, implement a matched impedance transmission line using microstrip or stripline techniques (consult an ECL design handbook for microstrip and stripline layout techniques). A 50-Ω environment is normally not necessary onboard, and in fact, a higher impedance environment improves distortion as shown in the distortion versus load plots. With a characteristic board trace impedance defined based on board material and trace dimensions, a matching series resistor into the trace from the output of the THS4271 is used as well as a terminating shunt resistor at the input of the destination device. Remember also that the terminating impedance is the parallel combination of the shunt resistor and the input impedance of the destination device: this total effective impedance should be set to match the trace impedance. If the 6-dB attenuation of a doubly terminated transmission line is unacceptable, a long trace can be series-terminated at the source end only. Treat the trace as a capacitive load in this case and set the series resistor value as shown in the plot of $R_{(ISO)}$ vs capacitive load. This does not preserve signal integrity or a doubly-terminated line. If the input impedance of the destination device is low, there is some signal attenuation due to the voltage divider formed by the series output into the terminating impedance.

5. **Socketing a high speed part like the THS4271 is not recommended.** The additional lead length and pin-to-pin capacitance introduced by the socket can create a troublesome parasitic network which can make it almost impossible to achieve a smooth, stable frequency response. Best results are obtained by soldering the THS4271 onto the board.

PowerPAD™ DESIGN CONSIDERATIONS

The THS4271 is available in a thermally-enhanced PowerPAD family of packages. These packages are constructed using a downset leadframe upon which the die is mounted [see Figure 90(a) and Figure 90(b)]. This arrangement results in the lead frame being exposed as a thermal pad on the underside of the package [see Figure 90(c)]. Because this thermal pad has direct thermal contact with the die, excellent thermal performance can be achieved by providing a good thermal path away from the thermal pad.

The PowerPAD package allows both assembly and thermal management in one manufacturing operation.

During the surface-mount solder operation (when the leads are being soldered), the thermal pad can also be soldered to a copper area underneath the package. Through the use of thermal paths within this copper area, heat can be conducted away from the package into either a ground plane or other heat dissipating device.

The PowerPAD package represents a breakthrough in combining the small area and ease of assembly of surface mount with the heretofore awkward mechanical methods of heatsinking.

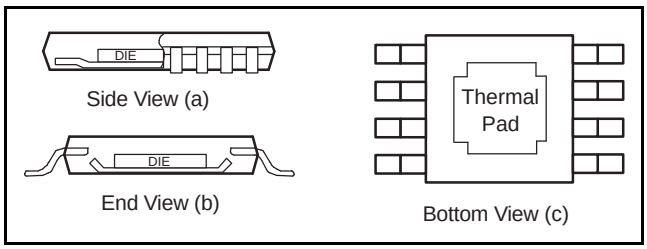


Figure 90. Views of Thermally Enhanced Package

Although there are many ways to properly heatsink the PowerPAD package, the following steps illustrate the recommended approach.

PowerPAD PCB LAYOUT CONSIDERATIONS

1. Prepare the PCB with a top side etch pattern as shown in Figure 91. There should be etch for the leads as well as etch for the thermal pad.

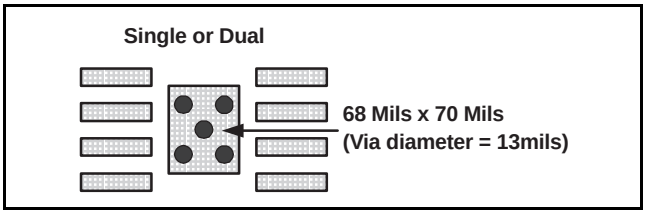


Figure 91. PowerPAD PCB Etch and Via Pattern

2. Place five holes in the area of the thermal pad. The holes should be 13 mils in diameter. Keep them small so that solder wicking through the holes is not a problem during reflow.
3. Additional vias may be placed anywhere along the thermal plane outside of the thermal pad area. They help dissipate the heat generated by the THS4271 IC. These additional vias may be larger than the 13-mil diameter vias directly under the thermal pad. They can be larger because they are not in the thermal pad area to be soldered, so that wicking is not a problem.
4. Connect all holes to the internal ground plane.
5. When connecting these holes to the ground plane, **do not** use the typical web or spoke via connection methodology. Web connections have a high thermal resistance connection that is useful for slowing the heat transfer during soldering operations. This resistance makes the soldering of vias that have plane connections easier. In this application, however, low thermal resistance is desired for the most efficient heat transfer. Therefore, the holes under the THS4271 PowerPAD package should make their connection to the internal ground plane, with a complete connection around the entire circumference of the plated-through hole.
6. The top-side solder mask should leave the terminals of the package and the thermal pad area with its five holes exposed. The bottom-side solder mask should cover the five holes of the thermal pad area. This prevents solder from being pulled away from the thermal pad area during the reflow process.
7. Apply solder paste to the exposed thermal pad area and all of the IC terminals.
8. With these preparatory steps in place, the IC is simply placed in position and run through the solder reflow operation as any standard surface-mount component. This results in a part that is properly installed.

For a given θ_{JA}, the maximum power dissipation is shown in Figure 92 and is calculated by the Equation 6:

$$P_D = \frac{T_{max} - T_A}{\theta_{JA}}$$

where:
P_D = Maximum power dissipation of THS4271 (watts)
T_{MAX} = Absolute maximum junction temperature (150°C)
T_A = Free-ambient temperature (°C)
$\theta_{JA} = \theta_{JC} + \theta_{CA}$
θ_{JC} = Thermal coefficient from junction to the case
θ_{CA} = Thermal coefficient from the case to ambient air (°C/W). (6)

The next consideration is the package constraints. The two sources of heat within an amplifier are quiescent power and output power. The designer should never forget about the quiescent heat generated within the device, especially multi-amplifier devices. Because these devices have linear output stages (Class AB), most of the heat dissipation is at low output voltages with high output currents.

The other key factor when dealing with power dissipation is how the devices are mounted on the PCB. The PowerPAD devices are extremely useful for heat dissipation. But, the device should always be soldered to a copper plane to fully use the heat dissipation properties of the PowerPAD. The SOIC package, on the other hand, is highly dependent on how it is mounted on the PCB. As more trace and copper area is placed around the device, θ_{JA} decreases and the heat dissipation capability increases. For a single package, the sum of the RMS output currents and voltages should be used to choose the proper package.

THERMAL ANALYSIS

The THS4271 device does not incorporate automatic thermal shutoff protection, so the designer must take care to ensure that the design does not violate the absolute maximum junction temperature of the device. Failure may result if the absolute maximum junction temperature of +150° C is exceeded.

The thermal characteristics of the device are dictated by the package and the PCB. Maximum power dissipation for a given package can be calculated using the following formula.

$$P_{Dmax} = \frac{T_{max} - T_A}{\theta_{JA}}$$

where:
P_{Dmax} is the maximum power dissipation in the amplifier (W).
T_{max} is the absolute maximum junction temperature (°C).
T_A is the ambient temperature (°C).
$\theta_{JA} = \theta_{JC} + \theta_{CA}$
θ_{JC} is the thermal coefficient from the silicon junctions to the case (°C/W).
θ_{CA} is the thermal coefficient from the case to ambient air (°C/W). (7)

For systems where heat dissipation is more critical, the THS4271 is offered in an 8-pin MSOP with PowerPAD. The thermal coefficient for the MSOP PowerPAD package is substantially improved over the traditional SOIC. Maximum power dissipation levels are depicted in the graph for the two packages. The data for the DGN package assumes a board layout that follows the PowerPAD layout guidelines referenced above and detailed in the PowerPAD application notes in the *Additional Reference Material* section at the end of the data sheet.

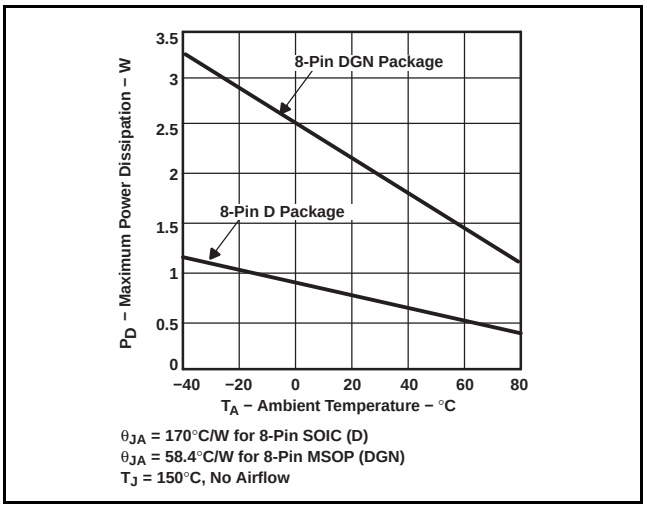


Figure 92. Maximum Power Dissipation vs Ambient Temperature

When determining whether or not the device satisfies the maximum power dissipation requirement, it is important to consider not only quiescent power dissipation, but also dynamic power dissipation. Often maximum power is difficult to quantify because the signal pattern is inconsistent, but an estimate of the RMS power dissipation can provide visibility into a possible problem.

DESIGN TOOLS

Performance vs Package Options

The THS4271 is offered in different package options. However, performance may be limited due to package parasitics and lead inductance in some packages. In order to achieve maximum performance of the THS4271, Texas Instruments recommends using the leadless MSOP (DRB) or MSOP (DGN) packages, in addition to proper high-speed PCB layout. Figure 93 shows the unity gain frequency response of the THS4271 using the leadless MSOP, MSOP, and SOIC package for comparison. Using the THS4271 in a unity gain with the SOIC package may result in the device becoming unstable. In higher gain configurations, this effect is mitigated by the reduced bandwidth. As such, the SOIC is suitable for application with gains equal to or higher than +2 V/V or (–1 V/V).

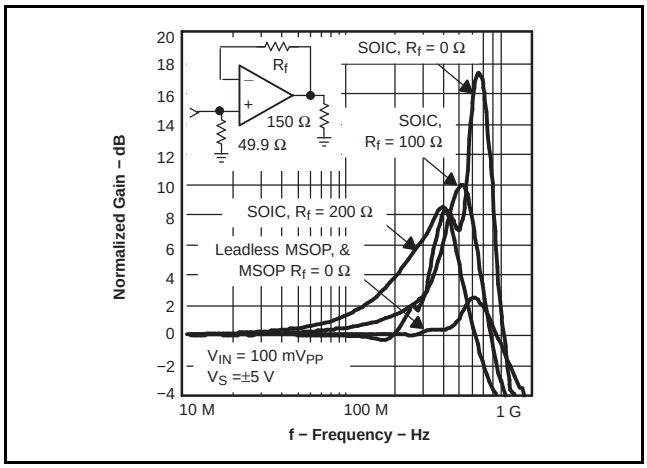


Figure 93. Effects of Unity Gain Frequency Response for DIfferential Packages

Evaluation Fixtures, Spice Models, and Applications Support

Texas Instruments is committed to providing its customers with the highest quality of applications support. To support this goal, evaluation boards have been developed for the THS4271 operational amplifier. Three evaluation boards are available: one THS4271, both are configurable for different gains, and a third for a gain of +1. These boards are easy to use, allowing for straightforward evaluation of the device. These evaluation boards can be ordered through the Texas Instruments web site, www.ti.com, or through your local Texas Instruments sales representative. Schematics for the evaluation boards are shown below.

The THS4271 EVM board shown in Figure 97 through Figure 100 is designed to accommodate different gain configurations. Its default component values are set to give a gain of 2. The EVM can be configured in a gain of +1; however, it is strongly not recommended. Evaluating the THS4271 in a gain of 1 using this EVM may cause the part to become unstable. The stability of the device can be controlled by adding a large resistor in the feedback path, the performance is sacrificed. Figure 94 shows the small-signal frequency response of the THS4271 with different feedback resistors in the feedback path. Figure 95 is the small frequency response of the THS4271 using the gain of 1 EVM.

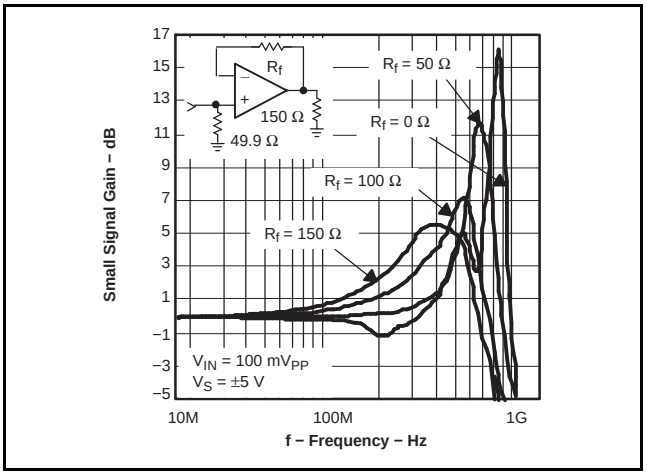


Figure 94. Frequency Response vs Feedback Resistor Using the EDGE #6439527 EVM

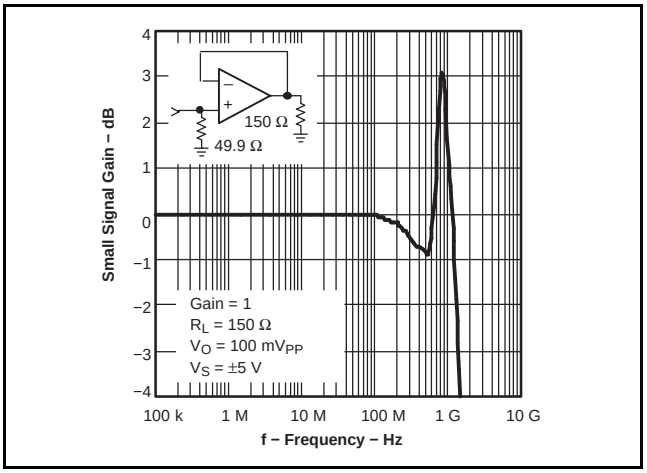


Figure 95. Frequency Response Using the EDGE #6443547 EVM

The peaking in the frequency response is due to the lead inductance in the feedback path. Each pad and trace on a PCB has an inductance associated with it, which in conjunction with the inductance associated with the package may cause peaking in the frequency response, causing the device to become unstable.

In order to achieve the maximum performance of the device, PCB layout is very critical. Texas Instruments has developed an EVM for the evaluation of the THS4271 in a gain of 1. The EVM is shown in Figure 102 through Figure 105. This EVM is designed to minimize peaking in the unity gain configuration.

Minimizing the inductance in the feedback path is critical for reducing the peaking of the frequency response in unity gain. The recommended maximum inductance allowed in the feedback path is 4 nH. This can be calculated by using Equation 8.

$$L(nH) = K\ell\left[\ln\frac{2\ell}{W + T} + 0.223\frac{W + T}{\ell} + 0.5\right] \quad (8)$$

where:
W = Width of trace in inches.
ℓ = Length of the trace in inches.
T = Thickness of the trace in inches.
K = 5.08 for dimensions in inches, and K = 2 for dimensions in cm.

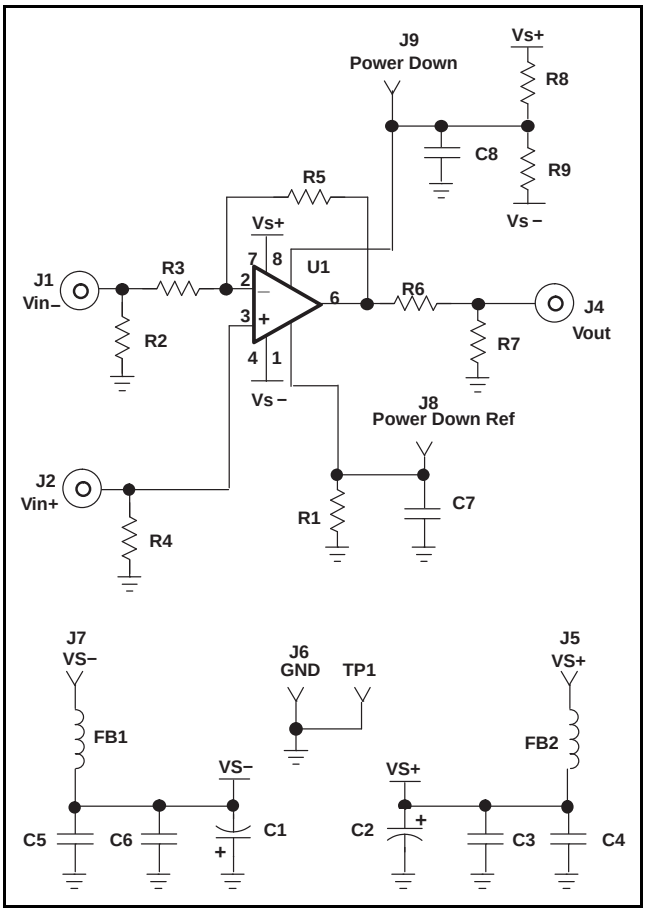


Figure 96. THS4271 EVM Circuit Configuration

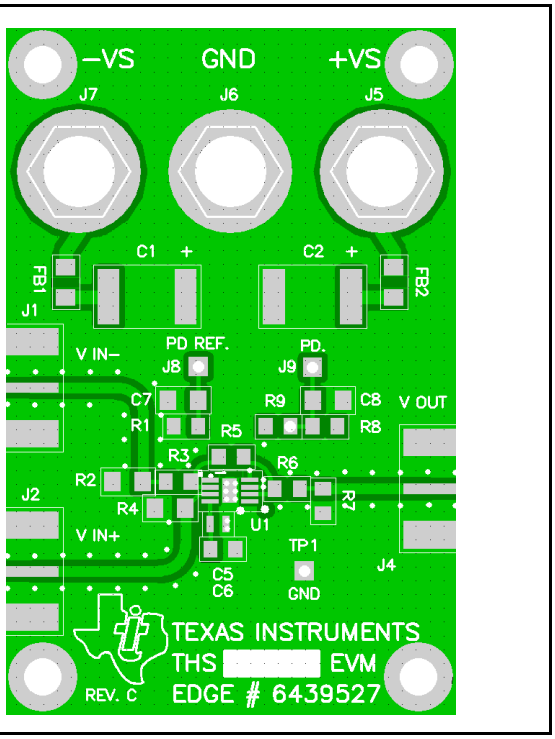


Figure 97. THS4271 EVM Board Layout (Top Layer)

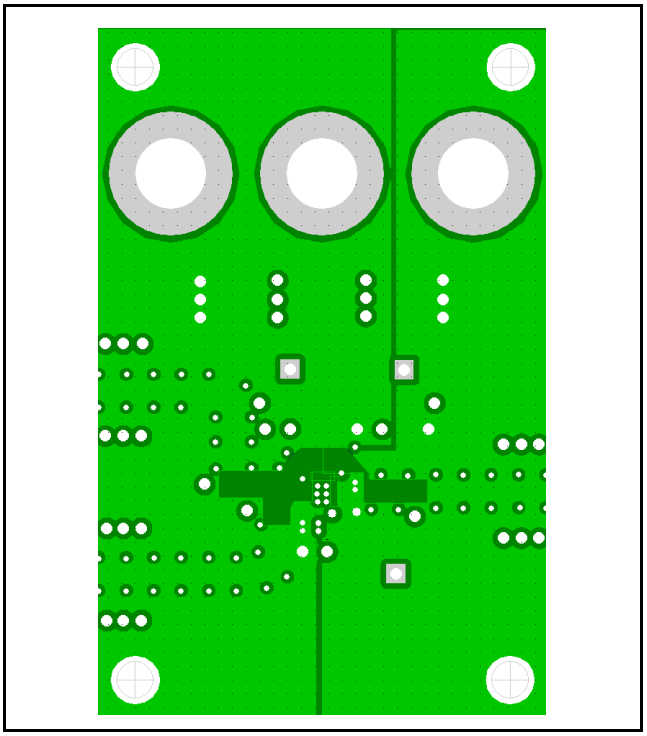


Figure 99. THS4271 EVM Board Layout (Third Layer, Power)

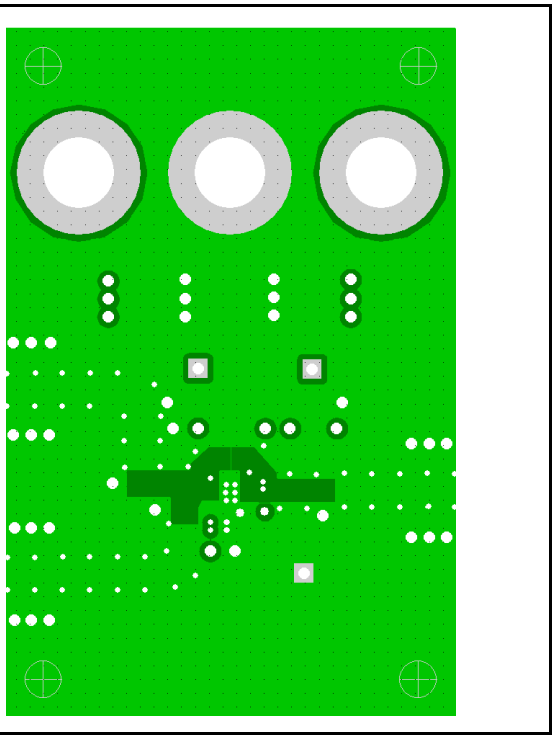


Figure 98. THS4271 EVM Board Layout (Second Layer, Ground)

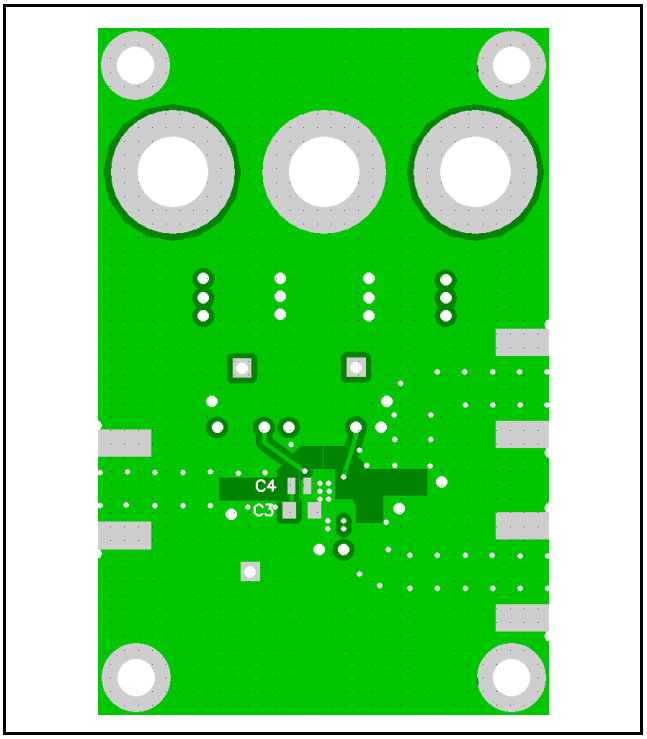


Figure 100. THS4271 EVM Board Layout (Bottom Layer)

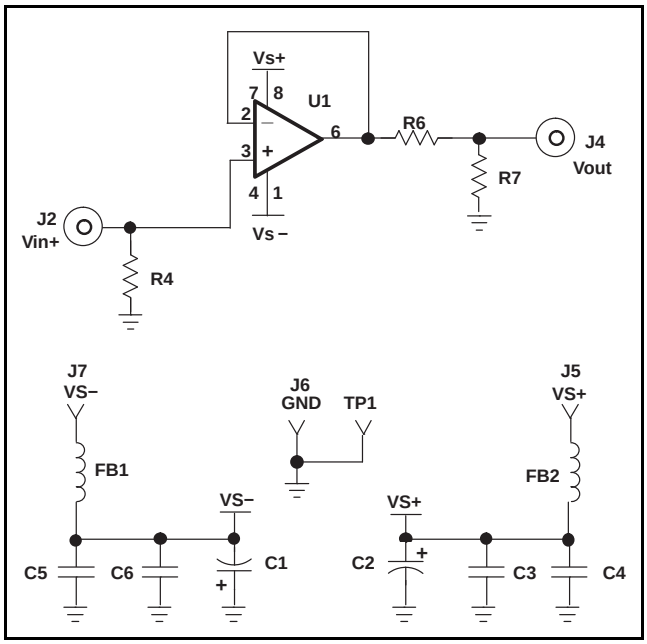


Figure 101. THS4271 Unity Gain EVM Circuit Configuration

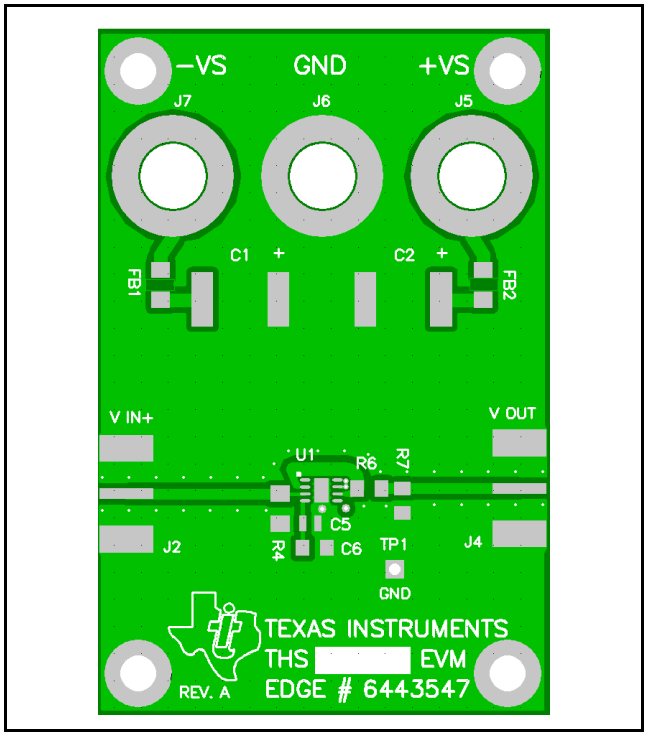


Figure 102. THS4271 Unity Gain EVM Board Layout (Top Layer)

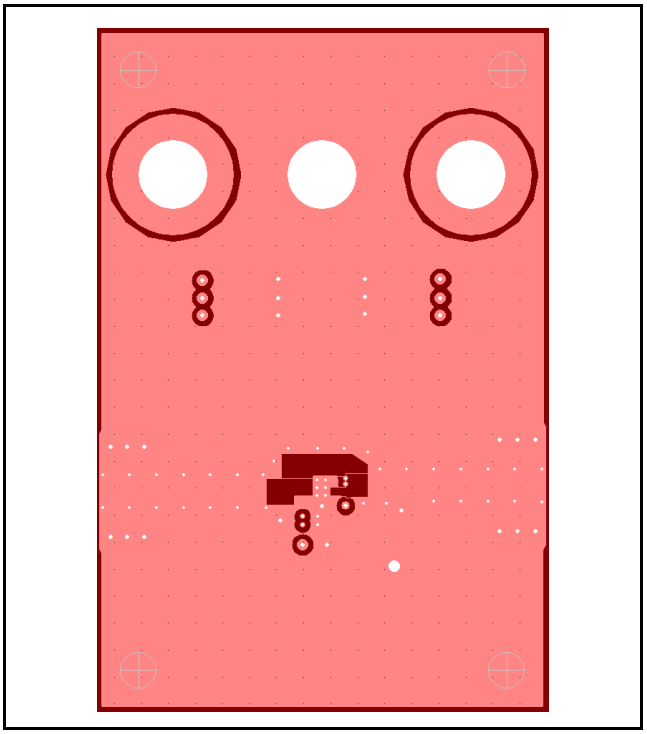


Figure 103. THS4271 Unity Gain EVM Board Layout (Second Layer, Ground)

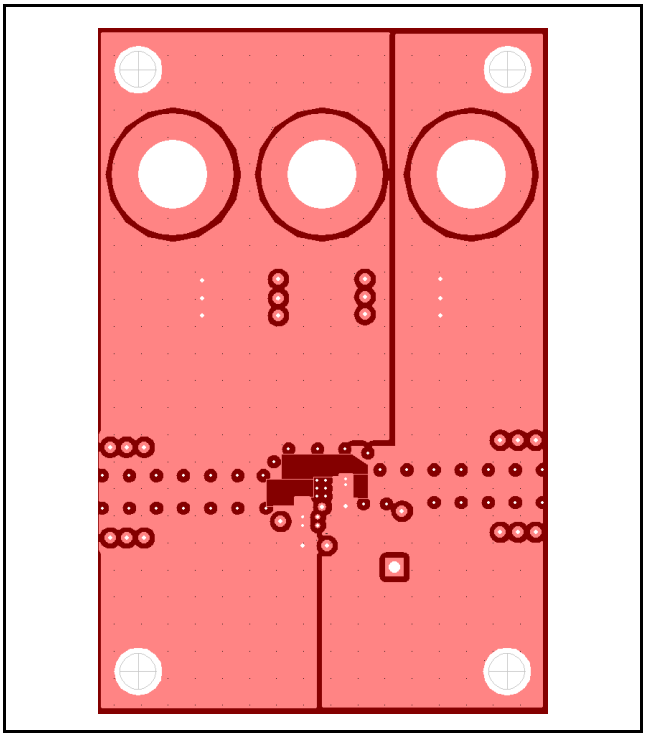


Figure 104. THS4271 Unity Gain EVM Board Layout (Third Layer, Power)

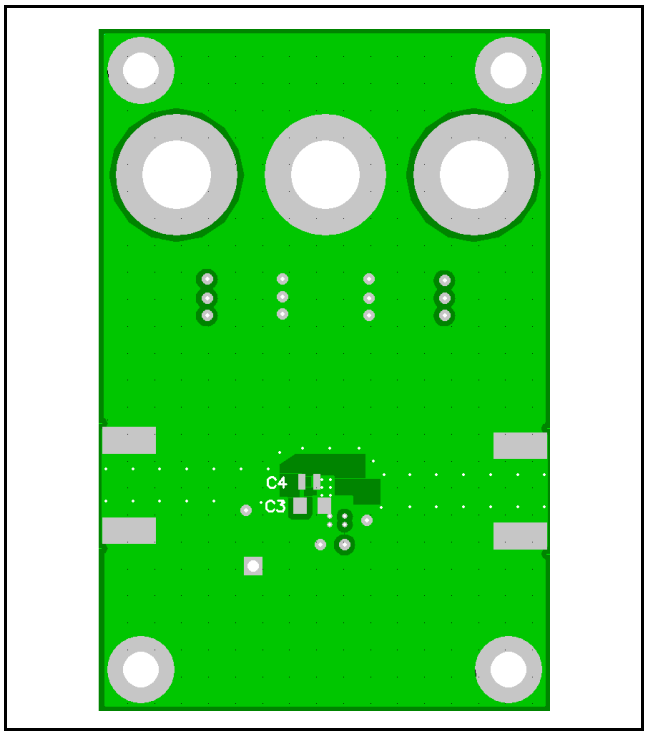


Figure 105. THS4271 Unity Gain EVM Board Layout

Computer simulation of circuit performance using SPICE is often useful when analyzing the performance of analog circuits and systems. This is particularly true for video and RF amplifier circuits where parasitic capacitance and inductance can have a major effect on circuit performance. A SPICE model for the THS4271 is available through either the Texas Instruments web site (www.ti.com) or as one model on a disk from the Texas Instruments Product Information Center (1-800-548-6132). The PIC is also available for design assistance and detailed product information at this number. These models do a good job of predicting small-signal ac and transient performance under a wide variety of operating conditions. They are not intended to model the distortion characteristics of the amplifier, nor do they attempt to distinguish between the package types in their small-signal ac performance. Detailed information about what is and is not modeled is contained in the model file itself.

ADDITIONAL REFERENCE MATERIALS

- *PowerPAD Made Easy*, application brief (SLMA004)
- *PowerPAD Thermally Enhanced Package*, technical brief (SLMA002)

REVISION HISTORY

SCOPE: Update specs to document device oscillation characteristics as the temperature exceeds 60°C. This documents the effort to reduce supply voltage range and reduce maximum junction temperature.

Changes from Revision B (July 2008) to Revision C **Page**

- Deleted THS4275-EP device 1
- Deleted D-8 package graphic 1
- Deleted "Power Down Functionality (THS4275)" and "Supply Voltage +12 V, +15 V" from FEATURES section 1
- Added "The THS4271 may…" paragraph to describe the device ocsilation characteristics and updated "THS4271 are low noise,…" to remove information pertaining to the THS4275 device within the DESCRIPTION section 1
- Deleted THS4275 devices, THS4271 D package devices and footnote (2) "Product Preview" from PACKAGING/ORDERING INFORMATION 2
- Added Maximum junction temperature to prevent oscillation to ABSOLUTE MAXIMUM RATINGS table 3
- Deleted D (8 pin) package information and footnote (2) due to THS4275 reference from PACKAGE DISSIPATION RATINGS section 3
- Deleted operating free air temperature specifications in RECOMMENDED OPERATING CONDITIONS table 4
- Changed MAX specification vlaues in RECOMMENDED OPERATING CONDITIONS table 4
- Deleted THS4275 device and D package designator for THS4271 device in PIN ASSIGNMENTS section 4
- Added footnote (1) "See application section…" to ELECTRICAL CHARACTERISTICS: V_S = ±5 V section 5
- Deleted Power Down Characteristics (THS4275 only) specifications to ELECTRICAL CHARACTERISTICS: V_S = ±5 V section 5
- Added footnote (1) "See application section…" to ELECTRICAL CHARACTERISTICS: V_S = 5 V section 7
- Deleted Power Down Characteristics (THS4275 only) specifications to ELECTRICAL CHARACTERISTICS: V_S = 5 V section 7
- Added MAXIMUM DIE TEMPERATURE TO PREVENT OSCILLATION section 20
- Deleted all THS4275 references from HIGH-SPEED OPERATIONAL AMPLIFIERS section 21
- Deleted Saving Power With Power-Down Functionality… section due to THS4275 reference 23
- Deleted POWER DOWN REFERENCE PIN OPERATION section due to THS4275 reference 23
- Deleted POWER SUPPLY DECOUPLING TECHNIQUE AND RECOMMENDATION section due to THS4275 reference 23
- Deleted THS4275 reference from NOISE ANALYSIS section 26
- Deleted THS4275 reference from PowerPAD™ DESIGN CONSIDERATIONS section 29
- Deleted THS4275 reference from DESIGN TOOLS section 31
- Deleted THS4275 reference 32
- Deleted THS4275 reference from Figure 97 33
- Deleted THS4275 reference from Figure 98 33
- Deleted THS4275 reference from Figure 99 33
- Deleted THS4275 reference from Figure 100 33

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
THS4271MDGNREP	Active	Production	HVSSOP (DGN) | 8	2500 | LARGE T&R	Yes	NIPDAUAG	Level-1-260C-UNLIM	-55 to 125	BLT
THS4271MDGNREP.A	Active	Production	HVSSOP (DGN) | 8	2500 | LARGE T&R	Yes	NIPDAUAG	Level-1-260C-UNLIM	-55 to 125	BLT
V62/05610-01YE	Active	Production	HVSSOP (DGN) | 8	2500 | LARGE T&R	Yes	NIPDAUAG	Level-1-260C-UNLIM	-55 to 125	BLT

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

OTHER QUALIFIED VERSIONS OF THS4271-EP :

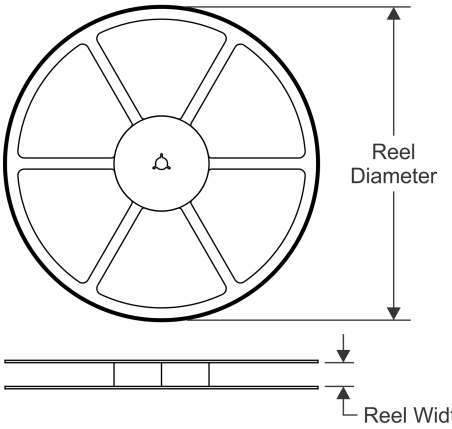
- Catalog : THS4271

NOTE: Qualified Version Definitions:

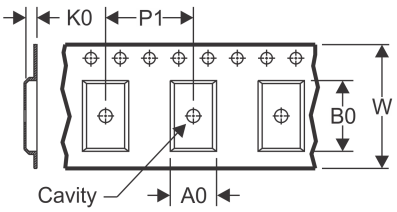
- Catalog - TI's standard catalog product

TAPE AND REEL INFORMATION

REEL DIMENSIONS

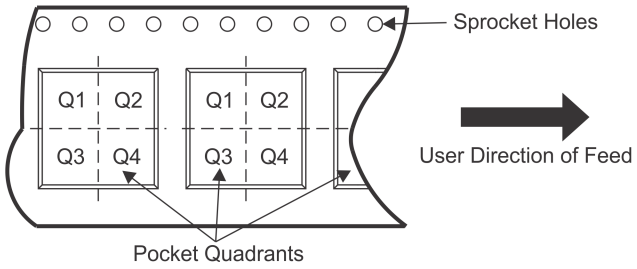


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

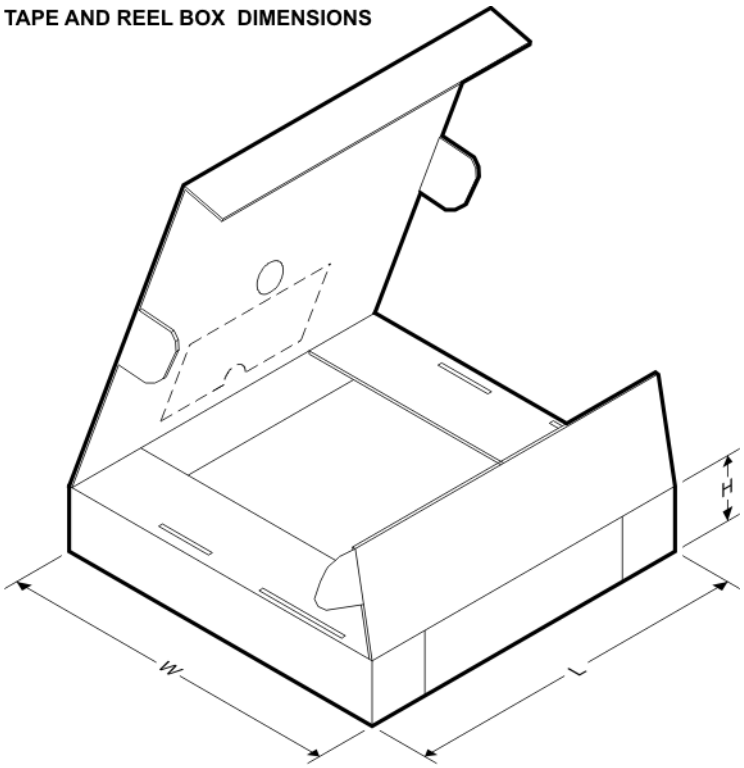
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THS4271MDGNREP	HVSSOP	DGN	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THS4271MDGNREP	HVSSOP	DGN	8	2500	358.0	335.0	35.0

GENERIC PACKAGE VIEW

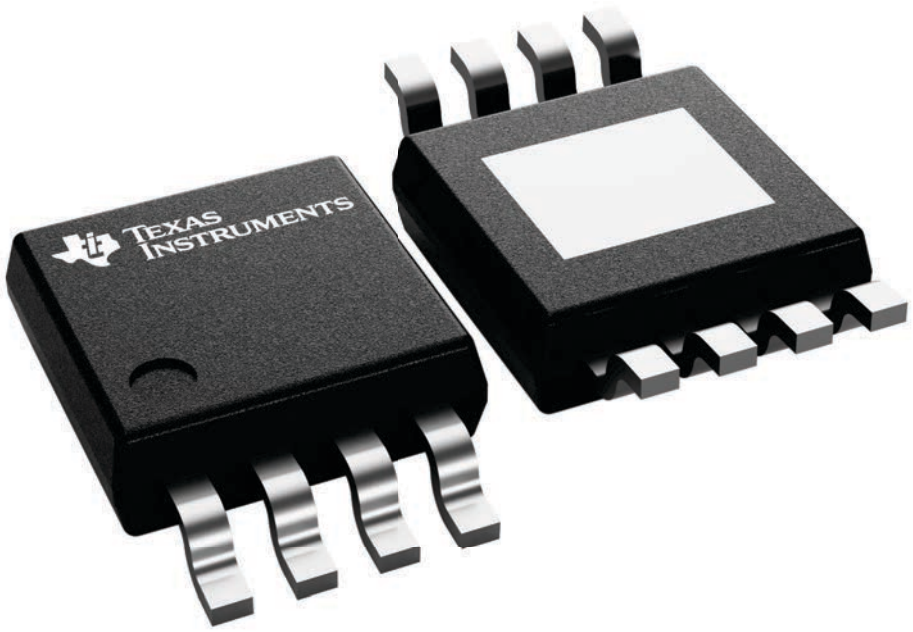
DGN 8

PowerPAD™ HVSSOP - 1.1 mm max height

3 x 3, 0.65 mm pitch

SMALL OUTLINE PACKAGE

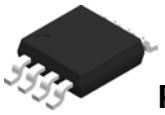
This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.



4225482/B

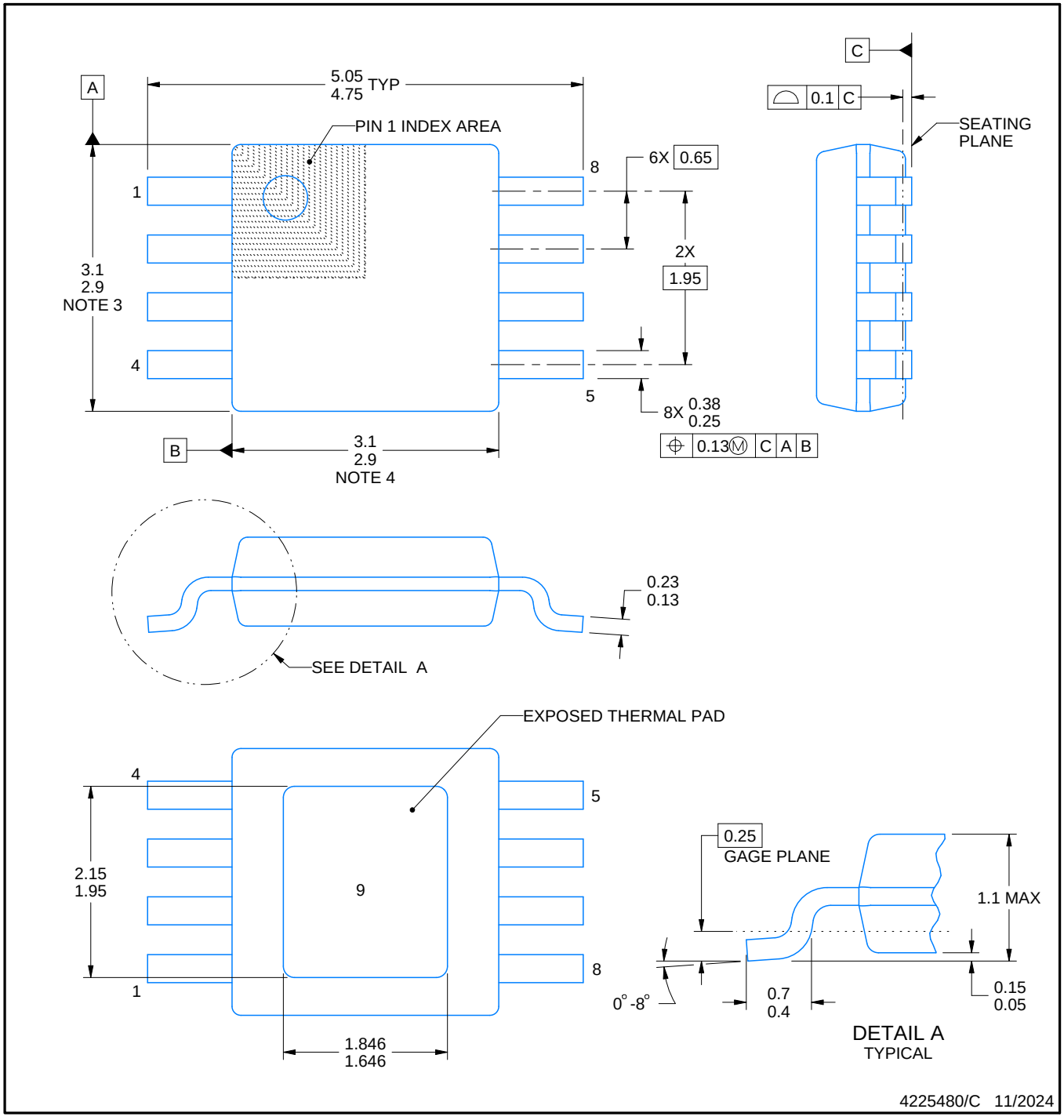
PACKAGE OUTLINE

DGN0008G



PowerPAD™ HVSSOP - 1.1 mm max height

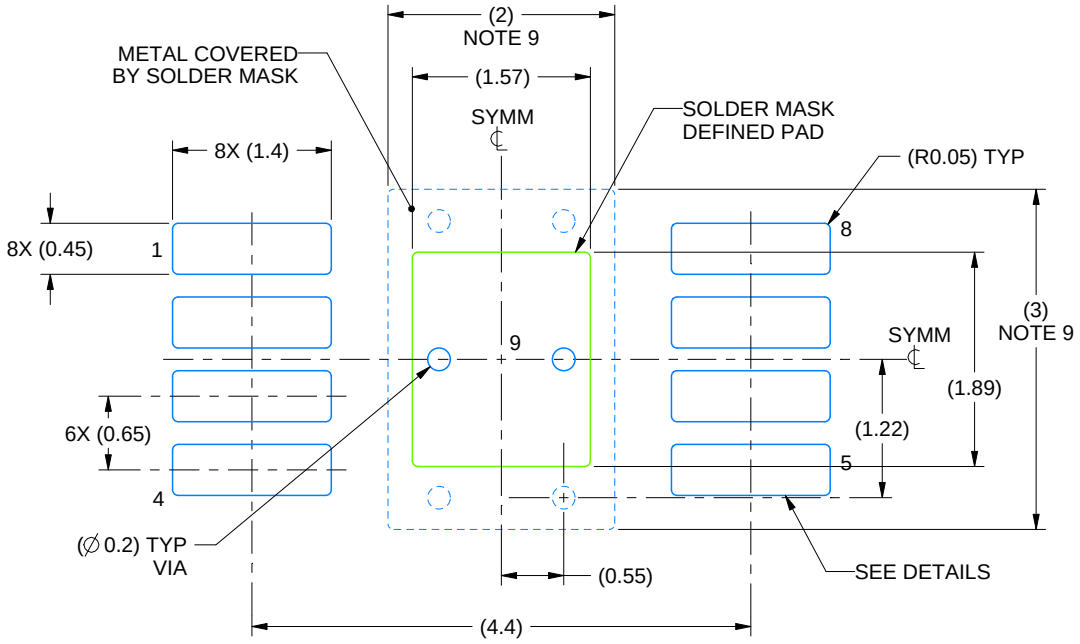
SMALL OUTLINE PACKAGE



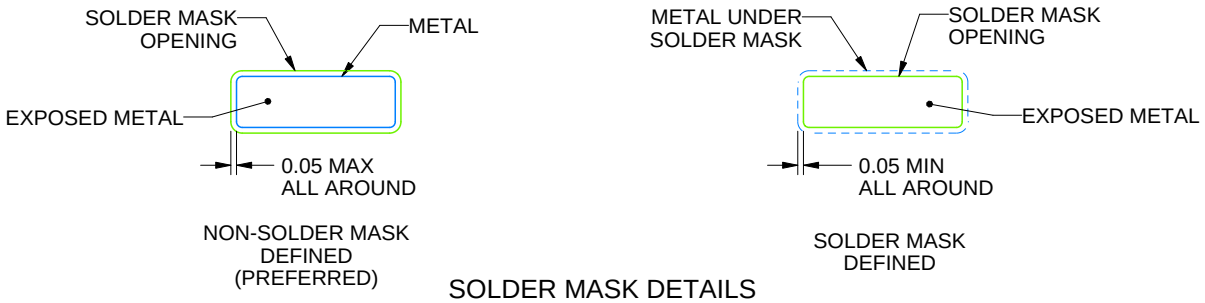
PowerPAD is a trademark of Texas Instruments.

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-187.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 15X



SOLDER MASK DETAILS

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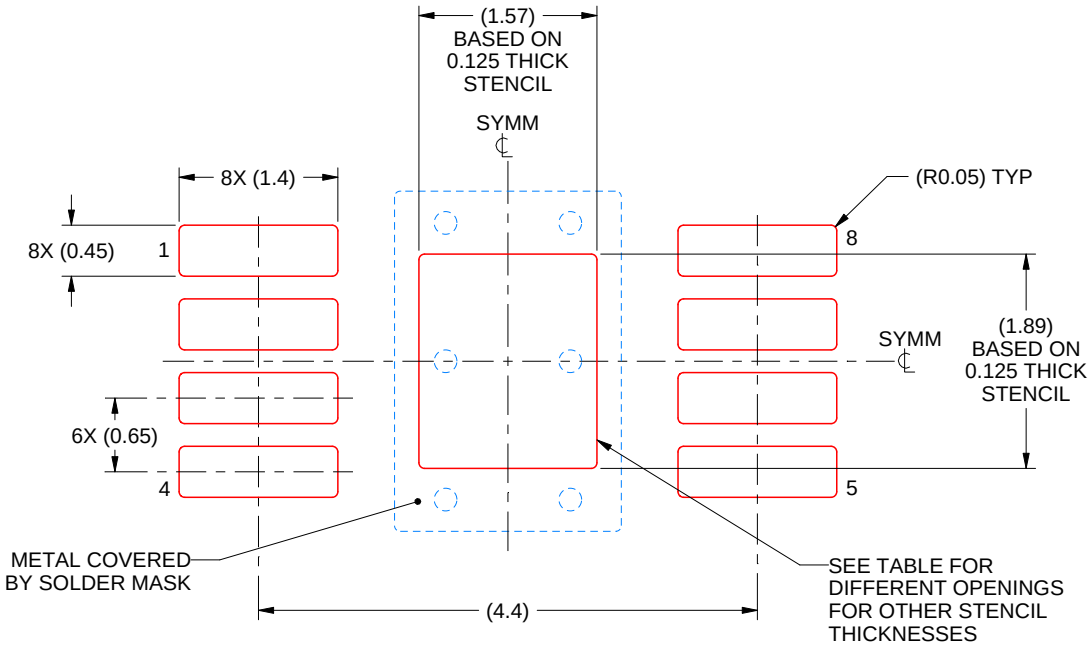
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
9. Size of metal pad may vary due to creepage requirement.



SOLDER PASTE EXAMPLE
EXPOSED PAD 9:
100% PRINTED SOLDER COVERAGE BY AREA
SCALE: 15X

STENCIL THICKNESS	SOLDER STENCIL OPENING
0.1	1.76 X 2.11
0.125	1.57 X 1.89 (SHOWN)
0.15	1.43 X 1.73
0.175	1.33 X 1.60

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NOTES: (continued)

10. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
11. Board assembly site may have different recommendations for stencil design.

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